

GR1687 **Megahertz** LC Digibridge[™]

Form 1687-0120-8

Instruction Manual

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GR1687 **Megahertz** LC Digibridge[™]

Form 1687-0120-8

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Specifications

Parameters Measured: Series L and Q; series C and D; series C and R; and parallel C and G. All are key selectable.

Measurement Rates: Slow (2/s typical), fast (4/s typical). Key selectable. Refer to accuracy statements for speed/accuracy data.

Test Frequency: 1.000 MHz ±.01 %

Measurement Ranges:

L = 00.001 to 99999 μ H

- $C = 00.001$ to 99999 pF
- $Q = 00.01$ to 999.9
- $D = .0001$ to 9.999
- $R = 00.01 \Omega$ to 999.9 k Ω $G = 00.01 \mu S$ to 999.9 mS
-

Main Displays: Key selectable.

• Value: L/a, C/O, C/R, C/G. Five full digits (99999) for L or C and four full digits (9999) for Q , D , R or G . Completely autoranging; decimal points and units included in display.

• Bin number: Identifies bin for tested component.
• Programmed limits for any bin

• Programmed limits for any bin.
• $\triangle 1\%$ or $\triangle C\%$: Percentage devia

 ΔL % or ΔC %: Percentage deviation of selected L or C measurement from stored nominal value.

Measurement Modes: Continuous, average (running average of 10 measurements), or single. Key selectable.

External Bias: Up to 60 V can be applied. On-off switch on keyboard; indicator shows when bias is applied. Bias source must be able to supply 15 mA dc with ripple less than 1 mV pk-pk. External discharge circuit recommended.

Applied Voltage: Nominal 0.1 V rms with 1687-9603 probe (supplied) or 1.0 V with -9604 probe (available). Actual voltage is nominal ±20% for high-Z OUT (C < 100 pF) and is loaded down by low-Z OUT (to $1/10$ of nominal for $C = 1600$ pF).

Accuracy: These specifications apply when the standard 0.1-V probe (1687-9603) is used:

These specifications apply when the optional 1-V probe (1687-9604) is used:

$$
L ACCURACY = \pm 0.05\%M \left[7 + \frac{L}{500 \mu H} + \frac{50 \mu H}{L}\right] \left[1 + 1/Q\right]
$$

C ACCURACY = ±0.05%M $3 + \frac{C}{500 \text{ sF}} + \frac{50 \text{ pF}}{2}$ | 1 + D α ACCURACY = \pm .01 + .002M (1 + α) α | | Basic L Accuracy 0.2% D ACCURACY = $\pm .002M$ | 1 + (1 + D) D | | Basic C Accuracy 0.2% R ACCURACY = ±0.05%M $\left[3 + \frac{R}{3 k \Omega} + \frac{300 \Omega}{R}\right] \left[1 + 1/D\right]$ G ACCURACY = ±0.05%M $\left[3 + \frac{G}{3 \text{ ms}} + \frac{300 \text{ }\mu\text{s}}{G}\right] \left[1 + 1/\text{D}\right]$ L 500 pF C J L J
Basic C Accuracy Cross Term

In above specifications,

M = 1, for SLOW measurement rate

M = 5, for FAST measurement rate

 $Q = \frac{2\pi fL}{R}$ for series L and R

$$
D = 2\pi f RC
$$
 for series R and C

 $D = \frac{G}{2\pi fC}$ for parallel G and C

 $f = 1$ MHz

Accuracy specifications apply after warmup (0.5 hr) up to 1 year after full recalibration, provided that ambient temperature is within limits stated under "Environment," below, within ±5°C of temperature during previous open/short calibration, and within $\pm 15^{\circ}$ C of temperature during previous full recalibration.

Recalibrations: Semiautomatic; operator follows simple keyboard routines and connects known terminations as follows: for open/ short recalibration, open and short circuits; for full recalibration, same and a 1OO-pF standard capacitor. Calibration kit recommended; see below.

Sorting: Limit comparator sorts vs a QDRG limit and up to 8 pairs of LC limits into 10 bins, conveniently defined by keyboard entries. GO/NO-GO is indicated, whether bin number or measured value is selected as main display.

Supplementary Displays: Modes, measurement rates, subject of main display, function, recalibration sequence. Indicators are labeled lights on keyboard.

Interface option: 2 ports (1 with choice of 2 modes); a 24-pin connector for each port. IEEE-488 INTERFACE PORT: Functions are SH1, AH1, T5, L4, SR1, RL2, PPO, OCO, OT1, CO. Refer to IEEE Standard 488-1975. Switch selection between 2 modes as follows. TALKER-LISTENER MODE: Input commands from system controller can disable keyboard and program all functions (except setting limits for sorting); any or all measurement results are available

as outputs. TALKER-ONLY MODE: Measured results are always output, for use in systems without controllers. HANDLER INTER-FACE PORT: 1 input (start signal), 2 output (status signals), and set of 10 output lines (sorting data); active-low logic; for input, logic low is 0.0 to +0.4 V (current is 0.4 mA max) and logic high is +2.4 to +5.0 V; for outputs, open-collector drivers rated at +30 V max, 40 mA max (sink), each, this port only. (External power supply and pullup resistors are required.)

Environment: Operating: $+0^\circ$ to $+50^\circ$ C, 0 to 85% relative humidity. Storage: -40° to +75 $^\circ$ C.

Supplied: O.l-V measurement probe with cable (1687-9603), condensed operating instruction card, instruction manual, bias cable, and power cord for 125-V ac line.

Available: Test fixture, for axial- and radial-lead parts, Kelvin connections. 1-V measurement probe on plug-in cable. Calibration Kit (includes precision short-circuit termination, precision open-circuit termination, 1OO-pF coaxial capacitance standard, test-fixture adaptor, and carrying case). 1405-9700 1-pF Coaxial Capacitance Standard. 1687-9602 Reference Standard Adaptor for test

fixture, to accept GR900[®]-series terminations and standards (included in -9605), Interface option (included in 1687-9701 or available separately). Replacement battery; (life expectancy in use is 5 years).

Power: 90 to 125 V or 180 to 250 V, 50 to 60 Hz. Either range selected by rear-panel switch. 36 W maximum.

Mechanical: Bench model.

Dimensions (wxhxd): 37.54x11.18x34.29 cm (14.78x4.4x13.5 in.). WEIGHT: 6.2 kg (13.5Ib) net, 8.2 kg (18 Ib) shipping.

Warranty

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Introduction- Section 1

1.1 PURPOSE.

The 1687 1-MHz LC DigibridgeTM is a digital impedance meter and limit comparator embodying use of a microprocessor and other LSI circuitry to provide convenience, speed, accuracy, and reliability at low cost. With the interface option, this Digibridge can control other equipment and respond to remote control.

The versatile probe, accessory test fixture, lighted keyboard, and angled display panel make this Digibridge convenient to use. Measurement results are clearly shown with decimal points and units, which are automatically presented to assure correctness. Display resolution is 5 digits for Land C (4 for Q, D, R, or G) and the basic accuracy is 0.1%.

Long-term accuracy and reliability are assured by the measurement system. It makes these accurate analog measurements without any critical internal adjustments. Calibration to account for any change of probe or test-fixture parameters is semiautomatic; the operator needs to provide only open-circuit and short-circuit conditions in the procedure.

The accessory test fixture, with a pair of plug-in adaptors, receives any common component part (axial-lead or radial-lead), so easily that insertion of the device under test (DUT) is a one-hand operation. True 4-terminal connections are made automatically_

Bias can be applied to capacitors being measured, by connection of an external voltage source and sliding a switch. Bias levels from 0 to 60 V are suitable.

The interface option provides full "talker/listener" and "talker only" capabilities consistent with the standard IEEE-488 Bus.* A separate connector also interfaces with component handling and sorting equipment.

1.2 GENERAL DESCRIPTION.

1.2.1 Basic Digibridge.

Convenience is enhanced by the arrangement of controls and auxiliary displays on the front ledge, with all controls for manual operation arranged in a small keyboard. Above and behind them, the display panel is inclined and recessed

to enhance visibility of digital readouts and indicators. These indicators and those at the keyboard serve to inform and guide the operator as he manipulates the simple controls, or to indicate that remote control is in effect.

The instrument stands on a table or bench top. The sturdy metal cabinet is durably finished, in keeping with the long-life circuitry inside. Glass-epoxy circuit boards interconnect and support high-qual ity components to assure years of dependable performance.

Adaptability to any common ac power line is assured by the removable power cord and the convenient line-voltage switch. Safety is enhanced by the fused, isolating power transformer and the 3-wire connection.

1.2.2 Connections to the OUT.

The standard probe is supplied, with cable, to make 2-point connection to a component part or network to be measured. Connection is made by a pair of spring-loaded probe tips, which can be repositioned for a variety of terminal spacings. The probe is intended to be hand held and is most useful for measurement between nodes of a circuit board or terminals of a relatively large component part. Alternatively, the nose of the probe can be unplugged and set aside; then the probe-and-cable assembly will serve as a sophisticated cable that is used to connect to the test fixture described below. The entire probe-and-cable assembly can be unplugged from the Digibridge and replaced by another. In particular, the probe supplied with the instrument can be interchanged with an optional probe that has a higher test voltage.

The optional test fixture makes Kelvin connections directly on the wires of nearly any radial-lead or axial lead component part. This fixture is intended to stand on the bench near the Digibridge and to receive each part in such a way that insertion and removal are very simple one-handed operations. For radial-lead parts, the operator inserts each lead into a slot in the fixture. For axial-lead parts, an adaptor is first plugged into the fixture; then the operator slides the part between slotted posts so that each axial lead makes connection to a pair of hidden scissor-like blades.

1.2.3 Interface Option.

The interface option adds capabilities to the instrument,

^{·1} E E E Standard 488-1975, Standard Digital Interface for Programmable Instrumentation. (See para 2.8, below.)

Figure 1-1. Front controls and displays. Upper picture, whole instrument; lower, keyboard detail.

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enabling it to control and respond to parts handling/sorting equipment. Also (via separate connector) this option can be connected in a measurement system using the IE EE-488 Bus. Either "talker/listener" or "talker only" roles can be performed by the Digibridge, by switch selection.

1.2.4 References.

A functional description is given in Theory, Section 4. Electrical and physical characteristics are listed in Specifications at the front of this manual; dimensions, in Installation, Section 2. Controls are described below; their use, in Operation, Section 3.

1.3 CONTROLS, INDICATORS, AND CONNECTORS.

Figure 1-1 shows the controls and indicators on the front of the instrument. Table 1-1 identifies them with descriptions and functions. Similarly, Figure 1-2 shows the controls and connectors on the rear; Table 1-2 identifies them.

1.4 ACCESSORIES.

Gen Rad makes several accessories that enhance the usefulness of this Digibridge. The test fixture accepts nearly all radial- and axial-lead parts conveniently; and it is necessary for full recalibration. (Refer to Section 3.) A special probe brings a high test voltage to the OUT (with or without use of the test fixture). The calibration kit is necessary for full recalibration, unless an equivalent set of terminations, capacitance standard, and reference-standard adaptor are at hand. (See para 3.4.) Refer to Table 1-3 in this manual and the brochure of Impedance Standards and Precision Bridges, available from GenRad upon request.

Table 1-1 FRONT CONTROLS, INDICATORS, AND CONNECTIONS

INTRODUCTION 1-3

Table 1-1

FRONT CONTROLS, INDICATORS, AND CONNECTIONS (CONTINUED)

Figure 1-2. Rear controls and connectors.

Table 1-2 REAR CONNECTORS AND CONTROLS

*TALK switch and 24-pin connectors are supplied with the Interface Option only.

≪B

Table 1·3

ACCESSORIES

*Use one of the following if available: P/N LO-32 (Mallory Battery Co., S. Broadway, Tarrytown, N.Y. 10591), P/N 440S (Power
Conversion, Inc., 70 MacQuesten Pkwy S., Mount Vernon, N.Y. 10550), or P/N LR-2/3A (Matsushita E

B

Installation-Section 2

2.1 UNPACKING AND INSPECTION.

If the shipping carton is damaged, ask that the carrier's agent be present when the instrument is unpacked. Inspect the instrument for damage (scratches, dents, broken parts, etc.). If the instrument is damaged or fails to meet specifications, notify the carrier and the nearest Gen Rad field office. (See list at back of this manual.) Retain the shipping carton and the paddjng material for the carrier's inspection.

2.2 DIMENSIONS. Figure 2-1.

The instrument is supplied in a bench configuration, *i.e.*, in a cabinet with resilient feet for placement on a table. Overall dimensions are given in the figure.

2.3 POWER-LINE CONNECTION.

The power transformer primary windings can be switched, by means of the line voltage switch on the rear panel, to accommodate ac Iine voltages in either of 2 ranges, as labeled, at a frequency of 50 or 60 Hz, nominal. Using a small screwdriver, set this switch to match the measured voltage of your power line.

If your line voltage is in the lower range, connect the 3 wire power cable (P/N 4200-9625) to the power connector on the rear panel and then to the power line.

in conformance with the International Electrotechnical Commission publication 320. The 3 flat contacts are surrounded by a plastic shroud that reduces the possibility of electrical shock whenever the power cord is being unplugged from the instrument. In addition, the center ground pin is longer, which means that it mates first and disconnects last, for user protection. This panel connector is a standard 3-pin grounding-type receptacle, the design of which has been accepted world wide for electronic instrumentation. The connector is rated for 250 V at 6 A. The receptacle accepts power cords fitted with the Belden type SPH-386 connector.

The associated power cord for use with that receptacle, for line voltages up to 125 V, is GenRad part no. 4200-9625. It is a 210-cm (7 ft), 3-wire, 18-gage cable with connector bodies molded integrally with the jacket. The connector at the power-line end is a stackable hammerhead design that conforms to the *"Standard* for Grounding Type Attachment Plug Caps and Receptacles," ANSI C73.11-1966, which specifies limits of 125 V and 15 A. This power cord is approved for 125 V, 10 A, by Underwriters Laboratories, Inc.

If your power line voltage is in the higher range (up to 250 V), be sure to use a power cord that is approved for 250 V. The end that connects to the Digibridge should have

The instrument is fitted with a power connector that is

a connector of the type that is on the power cord supplied; the other end, an approved connector to mate with your standard receptacle. A typical configuration for a 250-V, 15-A plug is illustrated in Figure 2-2.

If the fuse must be replaced, be sure to use a "slow blow" fuse of the current and voltage ratings shown on the rear panel, regardless of the line voltage.

2.4 LINE-VOLTAGE REGULATION.

The accuracy of measurements accomplished with precision electronic test equipment operated from ac line sources can often be seriously degraded by fluctuations in primary input power. Line-voltage variations of ±15% are commonly encountered, even in laboratory environments. Although most modern electronic instruments incorporate some degree of regulation, possible power-source problems should be considered for every instrumentation setup. The use of line-voltage regulators between power lines and the test equipment is recommended as the only sure way to rule out the effects on measurement data of variations in line voltage.

2.5 TEST-FIXTURE CONNECTIONS.

An unusually versatile test fixture is available for this instrument and easily connected via the probe cable supplied. To connect common axial-lead or radial-lead component parts to be measured, you simply plug the device to be measured (DUT) into the test fixture, with or without its adaptors. For details, refer to para 3.2.

2.6 EXTERNAL BIAS.

WARNING

- Maximum bias voltage is 60 V. Do NOT exceed.
- Bias voltage is present at connectors, test fixtures, and on capacitors under test.
- Capacitors remain charged after measurement.
- Do not leave instrument unattended with bias applied.

Full bias voltage appears on test leads, bias-voltage source terminals, and on the leads of the DUT. Capacitors that have been measured with bias applied can be dangerous until properly discharged, if several of them become connected in series by chance contact. For safety, all personnel operating the instru ment with bias must be aware of the hazards, follow safe procedures, and remove bias before leaving the equipment unattended. Refer to para 3.7.

In order to measure a capacitor with dc bias voltage applied, connect an external voltage source as follows. Supply the desired dc voltage well filtered and current limited at 15 mA to 200 mA (max).

a. Plug the bias cable, supplied, into the BIAS connector, at the rear. The plug is keyed to enter the socket so that the red-tipped wire connects to the $+$ pin (as labeled at the BIAS connector).

b. Connect the black and red tips to the external bias supply $-$ and $+$ terminals, respectively.

An external discharge circuit is recommended, to reduce wear of the EXT BIAS switch of the Digibridge. If more than 30 V is sometimes used, a dual discharge circuit is recommended, as follows. One (to be used first) should have a 10-ohm resistor in series; the other (as a backup) should make a direct connection across the bias circuit.

If the measurement program warrants the expense of a remote test fixture (perhaps in conjunction with a handler), for biased capacitor measurements, it should be provided with the kind of circuit described above. It should have convenient switching to remove the bias source, to discharge through 10 ohms, and finally to short out the capacitor after measurement. For automated test setups, it is also feasible to precharge the capacitors before attachment to the test fixture and to discharge them after they have been removed. The equipment should be designed to safeguard personnel from electrical shock and adjusted to avoid the passage of large transient currents through the test fixture.

2.7 HANDLER INTERFACE (OPTION).

If you have the interface option, connect from the HANDLER INTERFACE on the rear panel to a handler,

Figure 2-2. Configuration of 250-V, 15-A plug. Dimensions in mm. This is listed as NEMA 6-15P. Use for example Hubbell plug number 5666.

printer, or other suitable peripheral equipment as follows. (The presence of the 24-pin connectors, shown in Figure 1-2, verifies the interface option.) Refer to Table 1-2 for the appropriate connector to use in making a cable. Refer to Table 2-1 for the key to signal names, functions, and pin numbers.

Table 2-1 HANDLER INTERFACE KEY

As indicated in the Specifications at the front of this manual, the output signals come from open-collector drivers that pull each signal line to a low voltage when that signal is active and let it float when inactive. Each external circuit must be powered by a positive voltage, up to 30 V (max), with sufficient impedance to limit the active-signal (logic low) current to 40 mA (max).

CAUTION

Provide protection from voltage spikes over 30 V.

The cautionary note above means typically that each relay or other inductive load requires a rectifier across it (cathode connected to the power-supply end of the load).

The input signal is also active low and also requires a positive-voltage external circuit, which must pull the signal line down below +0.4 V but not less than 0 V (i.e., not nega-

tive). The logic-low current is 0.4 mA (max). For the inactive state (logic high), the external circuit must pull the signal line above +2.4 V, but not above +5 V.

Refer to Figure 2-2A for timing guidelines. Notice that START must have a duration of 1 μ s (minimum) in each state (high and low). If START is provided by a mechanical switch without debounce circuitry, the Digibridge will make many false starts; but these will not cause extraneous testresult signals if START is made to settle down (low) within 20 ms (maximum) of the first transition to high.

Measurement starts at time d, which is essentially the same as time b or c; measurement is completed at e. (The START signals are expanded for clarity.) Interval d-e, during which the OUT must remain connected, is 150 ms for FAST or 300 ms for SLOW MEASURE RATE. After interval e-f, which is 50 ms, measurement results are available for sorting, i.e., one of the BIN lines goes low. A few microseconds later, EOT goes low (can be used to set a latch holding the bin assignment). ACQ OVER, the selected BIN line, and EOT then stay low until the next start command.

Be sure the TALK switch is set to TALK ONLY, if the IEEE-488 bus is not used.

Figure 2-2A. Handler interface timing diagram. External circuitry must keep $a-b > 1$ μs , b-a > 1 μs , and (if START is not "debounced") $a-c < 20$ ms. The OUT can be disconnected after "e." The selected "BIN" line goes low at "f"; the others stay high.

2.8 IEEE-488 INTERFACE (OPTION).

Refer to CAUTION on page 3-16.

2.8.1 Purpose. **Figure 2-3.**

If you have the interface option, you can connect this instrument into a system (containing a number of devices such as instruments, apparatus, peripheral devices, and generally a controller or computer) in which each component meets IEEE Standard 488-1975, Standard Digital Interface for Programmable Instrumentation. A complete understanding of this Standard (about 80 pages) is necessary to understand in detail the purposes of the signals at the IEEE-488 INTERFACE connector at the rear panel of this instrument. Commendable introductions to the Standard and its application have been published separately, for example: "Standard Instrument Interface Simplifies System Design," by Ricci and Nelson, *Electronics,* Vol 47, No. 23, November 14, 1974.

NOTE

For copies of the Standard, order "I EEE Std 488-1975, IEEE Standard Digital Interface for Programmable Instrumentation," from lEEE Service Center, Department PB-8, 445 Hoes Lane, Piscataway, N.J. 08854.

Each device is connected to a system bus, in parallel, usually by the use of several stackable cables. Refer to the figure for a diagram of a hypothetical system. A full set of connections is 24 (16 signals plus shield and ground returns), as tabulated below and also in the Standard. Suitable cables, stackable at each end, are available from Component Manufacturing Service, Inc., West Bridgewater, MA 02379, U.S.A. (Their part number 2024/1 is for a 1-meter-long cable.)

This instrument will function as either a TALK/LISTEN or a TALK ONLY device in the system, depending on the position of the TALK switch. "TALK/LISTEN" denotes full programmability and is suited for use in a system that has a controller or computer to manage the data flow. The "handshake" routine assures that the active talker proceeds slowly enough for the slowest listener that is active, but is not limited by any inactive (unaddressed) listener. TALK ONLY is suited to a simpler system $-$ e.g., Digibridge and printer - with no controller and no other talker. Either mode provides measurement results to the active listeners in the system.

2.8.2 Interface Functions.

The following functions are implemented. Refer to the Standard for an explanation of the function subsets, represented by the identifications below. For example, T5

Figure 2-3. Block diagram of a generalized system interconnected by the 16-signal-line bus specified in the I EEE Standard 488. Reprinted from *Electronics,* November 14, 1974; copyright McGraw Hill, Inc., 1974.

represents the most complete set of talker capabilities, whereas PPO means the absence of a capability.

SH1, source handshake (talker)

AH1, acceptor handshake (listener)

T5, talker (full capability, serial poll)

L4, listener (but not listen-only)

SR1, request by device for service from controller

RL2, remote control (no local lockout, no return-tolocal switch)

PPO, no parallel poll

DC0, no device clear

DT1, device trigger (typically starts measurement)

CO, no controller functions.

The handshake cycle is the process whereby digital signals effect the transfer of each data byte by means of status and control signals. The cycle assures, for example, that the data byte has settled and all listeners are ready before the talker signals "data valid." Similarly, it assures that all listeners have accepted the byte before the talker signals "data not valid" and makes the transition to another byte. Three signal lines are involved, in addition to the 8 that convey the byte itself. Refer to Figure 2-4.

2.8.3 Signal Identification.

Refer to Table 2-2 for a key to signal names, functions, and pin numbers. Further explanation is found in the Standard. The first three signals listed take part in the "handshake" routine, used for any multiline message via the data bus; the next five are used to manage the flow of information; the last eight constitute the multiline message data bus.

2.8.4 Codes and Addresses.

The device-dependent messages, such as instrument programming commands and measurement data (which the digital interface exists to facilitate), have to be coded in a way that is compatible between talkers and listeners. They have to use the same language. Addresses have to be assigned, except in the case of a single "talker only" with one or more "listeners" always listening. The Standard sets ground rules for these codes and addresses.

In this instrument, codes for input and output data have been chosen in accordance with the rules. The address (for both tal ker and listener functions) is user selectable, as explained below.

Instrument Program Commands. Refer to Table 2-3. This input data code is a set of commands to which the instrument will respond as a "talker/listener," after being set to a remote code and addressed to listen to device-dependent command strings.

Notice that the set includes all the keyboard functions except entry of limits, which are not remotely programmable. Also, some of the remote-control commands have no manual-control equivalents. Data output commands enable selection of specific classes of measurement results, independently from the actual displays.

Each command is 2 bytes; each byte is coded according to the 7-bit ASCII code, using the ⁰¹⁰¹ ... ⁰¹⁰⁷ lines.* The most significant bit is D107, as recommended by the

^{*&}quot;X3.4-1968, Code for Information Interchange," available from American National Standards Institute, 1430 Broadway, New York, N. Y. 10018.

Figure 2-4. The handshake process, illustrated by timing diagrams of the pertinent signals for a system with one talker and several listeners. For details, refer to the Standard.

Standard. Thus, for example, the command for "Measure" is F1, having octal code 106 061. The 7-bit binary bytes are therefore: 1 000 110 and 0 110 001. (The ASCII code can be written out as follows. For the numerals 0, 1, 2...9, write the series of octal numbers 060, 061, ⁰⁶² ... 071; for the alphabet A, B, C... Z, write the series 101, 102, ¹⁰³ ... 132. Refer also to the table in the paragraph about "Address/' below. The A5C II code conforms to the 7-bit code 150 646 used internationally.) Notice that the eighth bit (D108) is ignored.

Address. The initial setting of address, provided by the factory, is binary 00011. Consequently, the tal k-address command (MTA) is C in ASCII code and, similarly, the listen-address command (MLA) is $#$. If a different address pair is desired, set it manually, using the following procedure.

WARNING

Because of shock hazard and presence of electronic dev ices su bject to damage by static electricity (conveyed by hands or tools), disassembly is strictly a "service" procedure.

a. Take the instrument to a qualified electronic technician who has the necessary equipment; refer to para 5.6. Have him remove the interface option assembly, as described in that paragraph. (There is no need to remove the top cover first.)

b. Have him set the switches in "DIP" switch assembly S2 to the desired address, which is a 5-bit binary number. (Refer to the comments below.)

c. Have him replace the interface option assembly in its former place.

Notice that S2 is located at the end of the interface option board, about 3 cm (1 in.) from the TALK switch S1. If S2 is covered, lift the cover off, exposing the "DIP" switch, which has 2 rows of 6 tiny square pads with numbers ¹ ... ⁶ between the rows. To enter logical 1's, depress pads nearest the end of the board. To enter logical O's, depress pads on the other side of the "DIP" switch, the side marked with $a + sign$. The address is read from 5 to 1 (not using 6). Thus, for example, to set up the address 00011, enter O's at positions 5, 4, 3; enter 1's at positions 2, 1. (This makes the talk address "c" and the listen address $'$: "#".) Strictly speaking, the address includes more; S2 determines only the device-dependent bits of the address. You cannot choose talk and listen addresses separately, only as a pair. The list of possible pairs is shown in Table 2-4.

In the above example, the remote message codes MLA and MTA are X0100011 and X1000011, respectively. Thus the listen address and the talk address are distinguished, although they contain the same set of device-dependent bits, which you set into S2.

Data Output. Data (results of measurements) are provided on the ⁰¹⁰¹ ... ⁰¹⁰⁷ lines as serial strings of

Table 2-2 IEEE-488 INTERFACE KEY

*"END" is typically sent concurrently with the delimiter "Iinefeed" character that terminates the string(s) of data output from the Digibridge (1,2, or 3 lines; see para 2.8.4).

* * I DY is not implemented in this Digibridge.

characters. Each character is a byte, coded according to the 7-bit ASCII code, as explained above. The alphanumeric characters used are appropriate to the data, for convenience in reading printouts. The character strings are always provided in the same sequence as that shown in Table 2-3; for example: LC value, $QDRG$ value, bin number $-$ if all 3 were selected by the X7 command. The carriage-return and Iinefeed characters at the end of each string provide a printer (for example) with the basic commands to print each string on a separate line.

For example, if the measurement was 32.500 pf, the character string for LC value is:

(space) (space) C (space) pF (3 spaces) 32.500 (CR) (LF). If a dissipation-factor measurement was 0.2345, the character string for QORG value is:

(space) (space) 0 (6 spaces) 0.2345 (CR) (LF).

If the measurement falls into bin 9, the character string for bin number is:

F (space) BIN (space) (space) 9 (CR) (LF).

The character string for LC value has a length of 17 characters; for QORG value, 17 characters; for bin number, 10 characters - including spaces, carriage-return, and linefeed characters. Refer to Tables 2-5, 2-6, and 2-7 for details.

Status. The Oigibridge responds with a status byte when the bus is in the serial poll mode and the Oigibridge is addressed to talk. The status is encoded as shown in Table 2-8 and sent on the data lines ⁰¹⁰¹ ... 0108.

2.8.5 Programming Guidelines.

If the Digibridge is to be programmed (TALK switch set to TALK/LISTEN), keep the following suggestions in mind. 1. An "unlisten" command is required before measure- • • Measurement-enabling sequence, for example: untalk
the Digibridge, send a GET, unlisten the Digibridge.

3. Then SRQ will not go false (high) until the Digibridge listen address (on Digibridge) satisfy the ATN false. has been addressed to talk or has been serially polled.

A typical program might include these features: • Initial setup: with ATN true, "untalk, unlisten, my 2.9 ENVIRONMENT. listen address (of Digibridge), my talk address (of CPU)"; The Digibridge can be operated in nearly any environ-

INSTRUMENT PROGRAM COMMANDS

the Digibridge, send a GET, unlisten the Digibridge.
• After CPU receives the SRQ, necessary enabling of 2. If not addressed to talk, the Digibridge sends a service **•** After CPU receives the SRQ, necessary enabling c

request (SRQ low) when it has data ready to send.

data transfer: with ATN true, "untalk, unlisten, my request (SRQ low) when it has data ready to send.
3. Then SRO will not go false (high) until the Digibridge and listen address (of CPU), my talk address (of Digibridge)";

then with ATN false, measurement conditions (Table 2·3). ment that is comfortable for the operator. Keep the instru-

* Enables entry of limits, which must be entered manually (para 3.6). * * Must be specified before initiation of measurement.

* An alternative "start" command is GET (group execute trigger), which is binary 0 001 000 in conjunction with ATN in the low state.

ment and all connections to the parts under test away from electromagnetic fields that may interfere with measurements.

Refer to the Specifications at the front of this manual for temperature and humidity tolerance and for the ranges of

* Do NOT set the switch to 11111, because ^a listen address of "?" would be confused with an "attention" command. (ASCII code for "underline" is 1 011 111, and for "?" is 0 111 111.)

temperature over which open/short calibration and full recalibration are valid, for best accuracy of measurement. To safeguard the instrument during storage or shipment, use protective packaging. Refer to Section 5.

Table 2-5 LC-VALUE DATA OUTPUT FORMAT

Table 2-6 QDRG-VALUE DATA OUTPUT FORMAT

2-8 **INSTALLATION**

Table 2-7 BIN-NUMBER DATA OUTPUT FORMAT

Table 2-8 STATUS CODE

B

OPERATION REFERENCE INFORMATION GenRad 1687 Digibridge[®]

1. GENERAL INFORMATION.

Refer to instruction manual for details of specification, installation, operation and service.

MEASUREMENT RANGES

2. AUTOMATIC INTERNAL SELF CHECK.

At power-on, the Digibridge thoroughly checks itself and normally goes into MEASURE function, CONT mode, C_S/D parameter, with corresponding displays. Check failure is indicated by LC display of 11111, 22222, 33333, or 44444; or function display of CAL. Failure also inhibits MEASURE function. (For 33333 failure, check that probe connects properly to its tip or test fixture; for CAL failure, complete recalibration is required.) Refer to manual, para 3.4.

3. CALIBRATION.

To correct for stray impedances in test fixture:

a. Select CAL with [FUNCTION] key.

b. Select OPEN with [CAL] key.

c. Open-circuit the OUT port of fixture or probe. For some fixtures this requires use of an open-circuit termination such as GR 900-WO; for others, simply the absence of OUT. Keep hands and stray objects 10 em away.

d. Press START. After about 5s, SHORT will light.

e. Short-circuit the OUT port. For some fixtures this requires the use of a known termination such as the GR 900- WN; for others, a short length of bus wire.

f. Press START. After about 5 s, STAND will light. A display of 55555 is normal. (Scale calibration with a standard capacitor can now be initiated using a special keying sequence; see instruction manual.) Normally, the previous scale calibration remains valid. To terminate this (shorter) procedure, press [FUNCTION]; see below.

4. OPERATION

a. Select MEASURE with the [FUNCTION] key.

b. 'Select measurement conditions with keys at right. Repeat keying advances selection as indicated nearby.

c. Select parameter with L_S/Q , C_S/D , C_S/R , or C_D/G_D key; note confirmation by light behind appropriate unit symbol on display panel. (Repeat keying has no effect except in entry mode; see para 6.)

d. Refer to manual for details of test fixture connections. Keep EXT BIAS switch OFF except when using bias.

e. Use START button for AVERAGE or SINGLE measure mode.

f. Read LC and QORG displays.

g. If limits have been entered and enabled (para 6), observe GO/NO-GO lights.

h. If limits have been entered and enabled (para 6), to see display of bin number instead of measured values, use [DISPLAY] key to select BIN No. and remeasure the OUT.

i. To display percent difference (delta) of measured value from previously stored reference, select $\Delta{\sf C}/\Delta{\sf L}$ with [DISPLAY] key.

j. To store the current LC measurement as reference for future use (step i): while the function is MEASURE, press the [NOM VALUE] key.

5. INTERFACE OPTION, USE OF IEEE-488 BUS.

Set the TALK switch (rear panel) as follows:

TALK ONLY-whenever bus is not in use and while communicating only with "listen-only" devices.

TALK/LISTEN-to enable use in a system with a controller device, e.g., calculator. Refer to table below for device-dependent messages to control Digibridge.

*Enables entry of bin limits, which must be entered via keyboard.

**Must be specified before initiation of measurement.

***An alternative command is given in manual.

6. ENTRY MODE.

Entry-mode keys are the left rear block of 16. Except for [NOM VALUE], they are effective only when the selected function is ENTER LIMITS.

*Use numerical and decimal-pt keys in sequence; max of 5 digits & dec pt valid even if display limited to 4.

**New nominal value does not affect bins already set up.

To resume operation using limits entered as above, press [FUNCTION] key. (See para 4.)

Operation- Section 3

3.1 BASIC PROCEDURE.

For initial familiarization, follow this procedure carefully. After that, use this as a ready reference and refer to later paragraphs in Operation for details.

Refer also to the Operation Reference Information, found stored in a pocket under the instrument. Reach under the front edge and pull the card forward as far as it slides easily. After use, slide it back in the pocket, for protection.

CAUTION

Set the line voltage switch properly (rear panel) before connecting the power cord.

a. Before connecting the power cord, slide the linevoltage switch (rear panel) to the position that corresponds to your power-line voltage. Power must be nominally 50 or 60 Hz ac, in either range: 90 to 125 V or 180 to 250 V.

Temperature. If the Digibridge has been very cold, warm it up in a dry environment, allowing time for the interior to reach 0° C or above, before applying power. Otherwise, the Digibridge may require a complete recalibration before it can be used.

Power Cord. Connect the power cord to the rear-panel connector, and then to your power line.

Power. Depress the POWER button so that is stays in the depressed position. (To turn the instrument off, push and release this button so that it remains in the released position.)

NOTE

Clean the leads of the OUT if they are noticeably dirty, even though the probe or test-fixture contacts will usually bite through a film of wax to provide adequate connections.

b. Connect a typical device, whose impedance is to be measured, as follows. (This device under test is denoted OUT.)

Probe. Press the probe nose against the 2 main terminals of the OUT, making good contacts with the probe tips. If appropriate, change one or both of the probe tips to another hole(s) in the probe nose. To do so, pull the tip out with your fingers and push it into the preferred hole. Be sure one tip is on each side of the center of the nose. (Each tip has 3 possible positions.)

Spacing of probe tips can be set from 3 to 16 mm apart (1/8 to 5/8 in.) between centers.

Test Fixture. Connect the OUT to the text fixture as described in para 3.2.

NOTE

For best accuracy of measurement, perform an open/short calibration (a simple procedure; see para 3.4) after each change of probe tip spacing or test fixture configuration, and at least once a day.

c. Choose the conditions of measurement. For the first 4 selections, below, the recommended choice is automatically provided when you switch the POWER ON. (To obtain another choice, press the corresponding key in the keyboard as many times as necessary, watching the indicator lights.)

Function: MEASURE DIsplay: VALUE Measurement Rate: SLOW Measurement Mode: CONTINUOUS External Bias Switch: OFF Talk Switch: TALK ONLY (rear panel).*

^{*}This switch is provided only if you have the Interface Option.

Parameter. For inductance, press Ls/Q; for capacitance, press Cs/O, Cs/Rs, or Cp/Gp; for resistance, press Cs/Rs; etc. The choice is confirmed by illumination of the appropriate unit label at bottom of display panel.

d. Read the measurement on the main displays. The LC display is the principal measurement, complete with decimal point and units which are indicated by the light spot in the lower part of the display panel. The QDRG display is shown similarly; the light spot indicates Q , D , or units for Rs or Gp, according to your parameter selection and the measurement.

NOTE

The following actions or conditions will abort measurements in progress or prevent measurement.

1. Pressing any key listed in step c above will abort the current measurement.

2. If there is no proper IE EE-488 system connection and the TALK switch on the rear panel is switched to TALK/LISTEN, continuous measurement is inhibited. (If you have the Interface Option, generally keep this switch set to TALK ONLY.)

3. Failure in the power-up self check will cause a display of 11111,22222,33333, or 44444; or the FUNCTION to be CAL. Refer to para 3.4.6.

3.2 CONNECTION OF THE OUT.

NOTE

Be sure POWER is switched OFF while you disconnect and/or connect probe, probe nose, or test fixture. Otherwise you lose benefits provided in the power-up self check.

3.2. 1 Standard Probe 1687-9603.

The standard probe (supplied) with its nose provides for convenient connection to many kinds of component parts and circujts having fairly solid terminals spaced about 2 to 17 mm apart. True 4-terminal connections are made within the nose of the probe. Source voltage is 0.1 V.

To change the spacing between tips, pull one or both out of the probe nose and push it into either of the other 2 holes on the same side of the probe's centerline. (Each tip has 3 locations.) Probe tips can be set at the following spacings: 3.2, 6.4, 9.5, 12.7, and 15.9 mm (1 to 5 eighths of an inch) between centers.

To connect the OUT, press the spring-loaded tips against the 2 main terminals of the OUT.

NOTE

After changing probe tip location, perform an open/short calibration. (See para 3.4.)

3.2.2 Large-Signal Probe 1687-9604.

The optional probe 1687-9604 makes measurements at a relatively high level (1-V source), at some sacrifice in accuracy. The instructions for its use are the same as for the standard probe, including use of the test fixture.

To exchange probes, use a narrow-bladed screwdriver to loosen the 2 captive screws left and right of the connector at the front edge of the Oigibridge and pull the connector directly forward. Then push the corresponding. connector of the other probe into the same place and tighten the 2 captive screws.

NOTE

After installing a different probe, perform a full recalibration of the Oigibridge.

Full recalibration requires the use of test fixture, adaptor, standards, etc., as described in para 3.4.

3.2.3 Use of Probe Nose.

To assure specified accuracy of measurements made with the probe-nose connection to a OUT, observe the operational details summarized below. See also para 3.4.

Be sure to repeat the open/short calibration after repositioning probe tips.

For the open-circuit portion of open/short calibration, depress the probe tips fully, against a suitable block of dielectric material. This is particularly important for measurement of small capacitance.

For the short-circuit portion of open/short calibration, depress the probe tips fully, against a suitable large-area conductor. This is particularly important for measurement of large capacitance.

Be aware of the effect of the probe nose on fringing fields. This is important for measurement of small-C capacitors with bulky terminals (hence relatively large fringing capacitance). Since the probe tips and nose must be in the fringing field during measurement, their presence increases the energy in that field. The consequent increase in the fringing capacitance is as much as 0.1 pF, for bulky, closely-spaced terminals; far less for small, well separated terminals. If this phenomenon is important in a particular measurement, position the probe nose where it encroaches as little as practicable into the dense part of the fringing field (the vicinity where opposite terminals are closest together, particularly if bulky).

However, if the OUT has terminals that match the test fixture, with or without adaptors, then measurement with the fixture is usually preferred to measurement with the probe nose.

3.2.4 Test Fixture 1687-9600. Figures 3-1, 3-2, 3-3.

The test fixture and its axial-lead adaptor (P/N 1687- 4100, included) together provide convenient, reliable,

Figure 3-1. Test fixture and accessories. 1 — Test fixture; see Table 1-3. 2 — Pair of slots for radial-lead DUT, labeled with polarity of bias, if any. 3 — Axial-lead adaptor. 4 — Probe and cable assembly, shown in position for plugging into test fixture. 5 -- Probe nose, shown unplugged from probe. 6 -- Thumb screw used to tighten clamp that holds probe securely in position. 7 - Connector that fits J8 on the front of the Digibridge.

Figure 3-3. Axial-lead OUT being measured in the test fixture, with adaptor.

4-terminal connection to any common radial-lead or axial-lead component part. Install the test fixture as follows.

a. Loosen the thumb screw in the clamp beside the large round hole in the back panel of the fixture.

b. Remove nose cone from the probe as follows. Using a 6-splined wrench, size 1.88 mm (0.074 in.), turn the setscrew near the nose end of the probe *inward*, free from the probe nose housing. A suitable wrench is supplied with the instrument. Pull the probe nose off in the axial direction. (Reassembly note: seat the setscrew by turning ccw; tighten gently.)

c. Insert probe carefully through the round hole in the fixture so the connector mates properly inside.

d. Finger tighten the thumb screw firmly, to lock the probe body in position.

The slots in the test fixture accommodate a pair of parallel wires of any diameter from 0.25 mm (0.01 in., AWG 30) to 1 mm (0.04 in., AWG 18), spaced from 6 to 81 mm apart (0.23 to 3.2 in.) or equivalent strip conductors. Each "radial" wire must be at least 0.8 cm long (0.3 in.). The divider between the test slots contains a shield, at guard (ground) potential, with its edge exposed. The axial-lead adaptor accommodates wires of any diameter up to 1.5 mm (0.06 in., AWG 15). The body of the OUT that will fit between these adaptors can be 62 mm

long and 41 mm diameter (2.4 x 1.6 in.) maximum. Each "axial" wire must be at least 3 mm long (0.12 in.).

For radial-lead parts. Remove the adaptor from the test fixture by loosening the 2 knurled captive screws and pulling the adaptor directly upward. Insert the DUT leads into the test-fixture slots.

For axial-lead parts. Insert the adaptor in the test fixture as follows.

a. Orient the adaptor with the screws (which are slightly off center) toward the rear of the test fixture.

b. Press the adaptor downward so that the contact blades enter the slots of the test fixture and the captive thumb screws enter their holes.

c. Finger tighten the thumb screws.

d. Slide the contact assemblies together or apart to accommodate the OUT to be measured. (Place them as close together as practicable if the DUT has short or fragile leads.)

General. Insert the DUT so one lead makes connection to each slot of the test fixture or adaptor. Insertion and removal are smooth, easy operations and connections are reliable if leads are reasonably clean and straight.

Be sure to remove any obvious dirt from leads before inserting them. The test-fixture contacts will wipe through a film of wax, but will become clogged and ineffectual if you are careless about cleanliness. Be sure the contact pair

inside each half of the test fixture or adaptor is held open by a single item ONLY. (Otherwise, you will not obtain true "Kelvin" connections to the DUT.)

3.2.5 Reference Standard Adaptor 1687-4600.

For connection of standards (necessary for full recalibration) or any ungrounded DUT having the $GR900^{\circledR}$ precision coaxial connector, attach the reference standard adaptor to the test fixture as follows. Notice that the outer conductor of this connector is not at ground potential and must not be grounded by the OUT. This adaptor is supplied in the 1687-9605 Calibration Kit.

a. Orient the adaptor so that the outer-conductor pin enters the *"_"* slot of the fixture. (This is consistent with the fact that the mounting screws are offset slightly from the centerline of the slots.)

b. Press the adaptor directly downward and finger tighten the thumb screws.

3.2.6 User's Cables. The Cables of the Cables of the Eigenberg S-4.

For connection of OUTs in test chambers, dielectric test cells, component handlers, or any arbitrary test fixture, make a cable as follows.

a. Obtain coaxial cable and connectors as listed:

1. GR 1687-8181 connector to mate with Digibridge probe. (Notice: this is a 2-cm, O.B-in., section containing 5 pairs of contacts, cut from a board-edge connector, Amphenol P/N 225-22521-401-117. Use the Amphenol part if it is available.)

2. Coaxial cable RG-174B/U, or equivalent. (Notice: higher-capacitance cable is not suitable for the length specified.)

3. Connector(s) if required to fit your test fixture. For

example, the banana plug and coaxial connector shown in the diagram are GR 274-P (P/N) 0274-9716) and GR 874-C58A (P/N 0874-9414), respectively.

b. Using 4 lengths of coaxial cable, each 30 cm long or shorter, connect from the board-edge connector to the test fixture or its connector as shown in the accompanying figure. Notice that the board-edge connector is shown as viewed from the wiring (back) side, positioned in the open end of the probe (probe nose removed). Mark the 1687- 8181 connector clearly so that it will always be plugged in properly. (Do not interchange "high" and "low" connections, thus reversing the bias polarity).

c. In general, make 5-terminal connections at the test end so that both "low" wires connect to one point and both "high" wires to another, as close as possible to the OUT. The coaxial-cable shields, which are at ground potential, should connect the shield or case (if any) of fixture or OUT. The alternative test-end connections shown in the figure are recommended for making measurements on samples in a test cell such as the Model LO-3, made by Balsbaugh Laboratories, South Hingham, Massachusetts.

Notice that there must be a rather low-resistance connection (10 Ω recommended) between the two "high" wires and another between the two "low" wires. Otherwise, there will be a failure in one of the power-up self checks; see para 3.4. The presence of these 10- Ω resistors at the far end of the cable does not invalidate the Kelvin connection. They should be physically small and electrically shielded from each other and the environment.

Connection to a wide variety of test fixtures and OUT configurations is possible by varying these instructions. Keep the cables short, the 4 critical wires shielded, and the geometry fixed. Conditions for open/short calibration must be reproducible and well defined for future reference.

Figure 3-4. Diagram of user's cable connection to any general OUT or test fixture. A recommended 3-wire connection is also shown, suited for use with certain test cells. In general, the 5 wires should not be left open circuited; connect from A to B through 1Oohms or less resistance and connect from C to D similarly.

3.3 ACCURACY AND SPEED.

3.3.1 General.

The basic accuracy of this Digibridge, with the probe supplied (with or without the recommended test fixture) is as follows: $\pm 0.1\%$ for C, $\pm 0.2\%$ for L, $\pm 0.14\%$ for R or G, ±0.004 for D, and ±0.012 for O. These specifications apply only for certain ranges of values, for suitable measurement conditions. Outside of these ranges and conditions, accuracy drops off in known ways, which should be understood by the operator. For example, selection of FAST measurement rate leads to less accurate measurements. To facilitate choice of conditions (if optional) and determination of accuracy for any particular results, refer to the accuracy statement in the specifications at the front of this manual, as well as the discussion of correcting for the inductance of the short circuit used in open/short calibration (para 3.4). Fringing effects are discussed in para 3.2.3.

Specified accuracy is presented conveniently in a set of graphs that show how accuracies of principal and secondary measured values depend on several factors.

3.3.2 LC and RG Basic Accuracy. Figure 3-5.

This graph shows the basic accuracy of the principal measured parameter L or C as a percent of measured value. Accuracy of secondary measurements R and G is shown also, being very similar. "Basic" accuracy is obtained when the cross term (i.e., quadrature component) is small.

A slightly different curve is shown for each type of parameter, L, C, or R (G). The effect of measurement rate is a factor of 5 in accuracy, as shown by a dual scale at the left.

Example: A low-D capacitor of 1000 pF is measured

using the SLOW measurement rate. The graph shows that accuracy is 0.15% or better.

3.3.3 L, C, R, or G Accuracy Factor. Figure 3-6.

This accuracy factor is the cross term, which must be multiplied by the basic accuracy to obtain accuracy for measurements of "impure" reactance or resistance. Notice that (unlike most of the graphed relationships) this formula is easier to use than its graph:

Accuracy factor = $1 + D$.

To use the accuracy-factor graph, first read D or Q on the Digibridge display. If the measurement of interest is R or G, temporarily select Cs/D with the appropriate parameter key, to obtain the value of D for entry into this graph.

Example: If the capacitor of the preceding example has a D of 0.5, the graph shows that the accuracy factor is 1.5. Therefore the accuracy of C measurement is $1.5 \times 0.15\% =$ 0.23%.

3.3.4 0 and Q Basic Accuracy. Figures 3-7, 3-8.

These graphs show the basic accuracy of D and Q measurements, as a percent of measured value. (Notice that the specifications are written in terms of absolute error rather than percentage.) This "basic" accuracy must be multiplied by the DO accuracy factor (right-hand scale in Figure 3-5) to obtain accuracy of measured D or O.

Example: If D is 0.5, the graph shows D basic accuracy is 0.35% (for SLOW rate). For a C of 1000 pF, the DO accuracy factor is about 1.5. Therefore D accuracy is: $1.5 \times 0.35\% = 0.53\%$.

Figure 3-5. LC and RG basic accuracy as a percent of reading, for each of the measurement rates. The DO accuracy factor (right-hand scale) is the multiplier that, applied to the basic DO accuracy, yields complete DO accuracy.

Figure 3-6. L, C, R, or G accuracy factor (or cross term) as a function of D or O. Multiply the basic accuracy (previous figure) by this factor to obtain the complete accuracy. Notice that for nearly "pure" reactance or resistance, this factor is unity.

Figure 3-7. D basic accuracy as a percent of reading (for capacitors). Each curve applies to one measurement rate, as labeled. For measurements of large or small capacitances, the D accuracy is somewhat worse than for medium capacitance; the complete D accuracy is the basic accuracy (this graph) multipled by the DO accuracy factor (Figure 3-5, right-hand scale).

3.3.5 Convenience of Logarithmic Scales.

The logarithmic scales on these figures make it easy to apply the accuracy factors visually, as distances along scales. In the preceding example, instead of reading a value of DO accuracy factor, mark on a scrap of paper the height of the C curve (at 1000 pF) above the base line (1) of the DO accuracy factor scale. On the D basic accuracy graph, point

to the basic accuracy on the vertical scale (0.35%); hold the scrap of paper adjacent to the scale and move the pointer up by the increment of height as marked; the point reached on this scale is the D accuracy (0.53%).

3.3.6 Measurement Rate.

Choose either of the two rates with the MEASURE

Figure 3-8. Q basic accuracy as a percent of reading (for inductors). Each curve applies to one measurement rate, as labeled. For measurement of large or small inductances, the Q accuracy is somewhat worse than for medium inductance; the complete Q accuracy is the basic accuracy (this graph) multiplied by the DO accuracy factor (Figure 3-5, right-hand scale).

RATE key: SLOW or FAST. The continuous-mode rates are respectively about 2 and 4 measurements per second. A SINGLE measurement takes essentially the same length of time after the START signal as each continuous-mode measurement; a set of AVERAGE measurements take 10 times longer. (The time required to change units or move the decimal point is negligible.)

3.4 CALIBRATION.

3.4.1 Introduction.

There are 2 distinct levels: open/short calibration (which provides in a convenient way the necessary correction for test fixture) and full recalibration.

Open/short calibration. This accounts for changes in *"stray"* impedances in test fixture, probe, etc. caused by changes in temperature or geometry. It should be performed after every change of test fixture, adaptor, spacing of probe tips or axial-lead adaptor contacts, etc. It should also be performed periodically, perhaps in the middle of each work day, even though test fixture geometry is not purposely changed.

Notice that accuracy specifications are met only for ambient temperature within $\pm 5^{\circ}$ C of the temperature at which the last open/short calibration was made.

Full recalibration. This procedure corrects for possible

long-term drift in the basic impedance-magnitude scale in the Digibridge or reestablishes scale calibration, which is retained in the form of numbers in a digital memory, in the event of loss (possibly by loss of battery voltage; see para 3.4.6). Full recalibration should be performed routinely once every 12 months and whenever large changes in ambient temperature are encountered, to assure specified accuracy of measurements.

Notice that accuracy specifications are met only for ambient temperature within $\pm 15^{\circ}$ C of the temperature at which the last full recalibration was made. Factory calibration is done at about 25°C.

3.4.2 Open/Short Calibration.

a. Set the geometry of the test fixture as desired for the anticipated measurements. In other words, install or remove adaptors as desired; set spacing of probe tips or movable adaptor parts appropriately. (This procedure is valid for a specific test-fixture geometry and must be repeated for each different geometry.)

NOTE

Be sure POWER is OFF while you are making any changes in connection among: instrument, probe, probe nose, and test fixture. Otherwise, you lose benefits provided in the power-up self check.

b. Switch the POWER ON. Select CAL with the [FUNCTION] key.

c. Select OPEN with the [CAL] key. Notice that the measure mode is automatically set to AVERAGE.

d. Open-circuit the OUT port of test fixture or probe. Keep hands and stray objects at least 10 cm away. Usually "open circuit" means simply the absence of a DUT. However, some measurements are defined with respect to a special open-circuit termination such as the GR 900-WO (which can be installed now if such measurements are anticipated).

If the probe is being used, with nose installed, make the correct open-circuit condition by pressing the tips against a block of low-loss, low-dielectric-constant material, using enough force to make the tips receded fully. Suggested materials are: polytetrafluoroethylene (Teflon), dry clean soft wood, polyethylene, polystyrene, polymethyl methacrylate (Lucite or Plexiglass), a thick pad of dry paper, or vinyl (listed in order of increasing dielectric constant).

e. Press the START button and keep away from the open port for five seconds or so, until the CAL indication changes from OPEN to SHORT. (Open-circuit data have now been stored.)

f. Short-circuit the OUT port of test fixture or probe, using a very low-impedance connection, for example:

1. Probe. Press contacts against thick ungrounded nonmagnetic conductor, such as copper sheet of at least 0.25 mm (.010 in.) thickness, 2.5×5 cm area (1 x 2 in.); or copper bar at least $1 \times 1 \times 3$ cm $(0.4 \times 0.4 \times 1$ in.). Depress tips fully.

2. Test fixture (1687-9600) with axial-lead adaptor. Slide the contact assemblies to closest spacing; insert short length of 1-mm (AWG 18) bus wire.

3. Same test fixture without adaptor. Insert a small U-shaped piece of 1-mm (AWG 18) bus wire, initial length 3 cm (1.2 in.); be sure it does not touch edge of shield between the slots.

4. Same test fixture with adaptor to GR900[®] connector. Use a GR 900-WN Precision Short-Circuit Termination.

g. Confirm that the CAL indication is SHORT. Press START and wait for 5 s or so until this indication changes from SHORT to STAND. (Short-circuit data have now been stored.) The LC display of 55555 is now normal.

h. Record the ambient temperature for reference by the operator.

i. Terminate this procedure and proceed with other uses of the Digibridge by selecting MEASURE or ENTER with the [FUNCTION] key, the desired mode with [MEASURE MODE] key, etc.

3.4.3 Full Recalibration. Figure 3-9.

The necessary and optional equipment for full recalibration is listed in Table 3-1. The procedure is as follows.

a. Establish the ambient temperature as desired,

normally $23^{\circ} \pm 3^{\circ}$ C. For special applications, this can be anywhere in the operating temperature range $(0^{\circ}$ to 50° C). Switch POWER ON, and allow 30 minutes "warmup," for all interior circuits to reach equilibrium.

b. Determine the capacitance to be added by the particular 1OO-pF standard, as follows. Read the certified 1-kHz value from its certificate of calibration. Be sure to correct for temperature, if appropriate to do so. (1-MHz correction is negligible.) From this value, subtract as follows.

If the 1-pF standard is not available, subtract the effective capacitance of the open-circuit termination (0.172 pF $± 0.008 pF$).

Alternatively, for even higher precision, if the 1-pF standard is available, find the certified value of the 100-pF standard and subtract the certified value of the 1-pF standard.

c. Remove the nose from the probe and connect probe to test fixture. Install the reference standard adaptor. Refer to Table 3-1 and para 3.2. (If subsequent measurements require a change of probe, make the change now, before recalibration. Keep POWER OFF during the change.)

d. With the [FUNCTION] key, select ENTER. Use normal entry procedure to enter as "nominal": the value determined in step b. For example:

[9] [9] [.] [7] [8] [3] [=] [NOM VALUE]. (The displayed number may change very slightly, reflecting use of binary math in the CPU.)

e. Perform the open/short calibration, in the usual way. That is, follow the procedure of para 3.4.2, steps b through g. In step d, use the open-circuit termination or the 1-pF standard, whichever was accounted for in step b of the present procedure. In step f of that procedure, use the short-circuit termination.

Confirm that the LC display is now 55555, indicating that "calibration interlock" is in effect.

f. Connect the 1OO-pF standard as 0 UT. The capacitance thus added has already been entered as " nominal value."

g. Initiate the scale calibration process by pressing these keys in sequence:

[=] [NOM VALUE] [START].

(No other sequence will operate the interlock.) Observe that the 55555 display disappears after the second keystroke, but that the CAL indication remains at STAND for a time after you press START. Make no changes while STAND remains lit. When this light goes out, scale calibration is complete.

h. Record the ambient temperature for reference.

i. If the next measurement is to be made on the reference-standard adaptor, and if the open-circuit termination was used (not the 1-pF standard) in the procedure above (steps b, e), then proceed to use the Digibridge by selecting MEASURE or ENTER with the [FUNCTION] key, the desired mode with [MEASURE MODE] key, etc.

However, if any change is needed in the test fixture, make the change and perform an open/short calibration (para 3.4.2) before measuring.

Figure 3-9. Calibration setup. The coaxial capacitance standard is shown on the referencestandard adaptor, on the test fixture.

Table 3-1 CALIBRATION EQUIPMENT

* Included in kit.

NOTE

Measurements of capacitors fitted with GR900 connectors (on the fixture as set up for full recalibration) yield the *effective* value of capacitance which is smaller than the value calibrated by Gen Rad. See below.

3.4.4 Effective Capacitance of Coaxial Precision Capacitors. The calibrated value of a GR coaxial capacitance standard with a GR900 connector is regularly determined to include the electric fields up to the reference plane of the connector when mated to another, without any fringing fields. (Some capacitance bridges can be "zeroed" to read this calibrated value directly.) However, this Oigibridge is automatically "zeroed" by the open-circuit data obtained (typically) with a GR900-WO open-circuit termination, which has a capacitance, beyond the reference plane of 0.172 pF \pm 0.008 pF (most of which is "fringing capacitance"). In a sense, the effective reference plane is out slightly (away from the test fixture) versus the reference plane of the connector. Therefore, when a coaxial capacitance standard is measured as a OUT, the Oigibridge measures it with respect to an effective reference plane slightly toward the capacitor from the reference plane of the connector.

The Oigibridge capacitance measurement is the difference between the capacitance of the DUT on the test fixture and the "zero" determined by the open-circuit termination. In practical terms, add the "zero" capacitance (0.172 pF) to the Oigibridge-measured (effective) value of a coaxial capacitance standard to obtain the intrinsic value comparable to its certification.

Notice that there is no easy way to eliminate this fringing effect. If the open-circuit correction (para 3.4.2) was

made with the reference-standard adaptor truly "open," the fringing capacitance would be only slightly smaller (about 0.155 pF) and would be less well known.

Also notice that for many measurements, the "zero" of an open-circuited test fixture is the generally accepted reference. (The value of a DUT is the change it introduces when connected to that fixture.)

3.4.5 Correction for Inductance of the Short Circuit.

For best accuracy in measurements of electrically very small inductors or very large capacitors, a correction should be made to the Digibridge reading, to account for the fact that the short circuit used in the open/short calibration does have some finite inductance.

The low-impedance short circuits recommended above (para 3.4.2) have sufficiently low inductances so that the Digibridge will meet specifications without correction, except for the U-shaped bus wire used in the test fixture without adaptor. For the purpose of this.correction, assume that short circuit has inductance of .010 μ H (L in the following calculations).

For small inductors with closely spaced radial leads. Add the inductance of the short circuit (L above) to the Digibridge readout of inductance.

For large capacitors with closely spaced radial leads. Use the following formula:

 $C' = C(1 - \omega^2 LC)$

where C' = corrected measurement; C = Digibridge capacitance readout; $\omega^2 = 40 \times 10^{12} =$ square of 2 x π x frequency; and $L =$ inductance of short circuit. (See above.)

Notice that the correction for L = .010 μ H is a fine point. L could be increased to .025 μ H before the effect on measurement accuracy (uncorrected) would be to double the error allowed in the performance specifications, for small- L or large-C measurements. Also notice that the corrections described above are completely negligible for inductors larger than 500 μ H and capacitors smaller than 100 pF.

3.4.6 Power-Up Self Check.

If the Digibridge displays one of the following indications when you switch POWER ON, there has been a failure in the automatic self check. The nature of the failure and the proper remedy for each are indicated below. Normal operation is inhibited in each of these cases.

11111 1111. The random-access-memory read/write exercise was imperfect. Try power-up again; otherwise the remedy is beyond the operator's control; repair service is required.

22222 XXXX. The detector/converter half-scale (zero) test was not completed satisfactorily. Remedy is the same as above. (The QDRG display provides some service information.)

33333 XXXX. The front-end test failed. Check carefully

that a probe/cable assembly is installed and that it is properly terminated. Either the probe nose or 1687-9600 Test Fixture is a proper termination. If you have a 5-wire user's cable instead (refer to Figure 3-4), there must be a low-impedance connection, 10 Ω or less, between A and B and another between C and D. Switch POWER OFF and ON again. If these remedies are ineffective, repair service is required.

44444 4444. The dual-slope converter/detector timeout has been invoked; there has been an invalid measurement. This can occur during power-up self check or during any measurement. (An all-4s display flashing alternately with measurement results will indicate an intermittent fault.) Seek repair service.

CAL. If FUNCTION is automatically set to CAL at power-up, there has been a loss of calibration data stored in random-access memory. A possible cause is low battery voltage. (Life expectancy of battery, at least in dry climate, is 5 to 10 years.) Refer to Table 1-3 for replacement part numbers. Replacement, although easy to do, is a repair/ service procedure. (Para 5.8.)

The Digibridge can be used with low battery voltage by performing a full recalibration each time POWER is turned ON. However, such a recourse is NOT recommended for regular practice. Replace the battery as soon as possible.

Another possible cause for loss of calibration· data is attempted operation while the internal temperature is too cold (even though the environment may be warmer). Allow the internal parts to come up to specified operating temperature (0° to 50° C) in a warm DRY environment before power-up. Then recalibrate if necessary.

3.5 PARAMETER AND MODE.

3.5.1 Parameter.

General. The selection of the parameter to be measured is almost self-explanatory. Depress the appropriate button: Ls/Q, Cs/D, Cs/Rs, or Cp/Gp. The readout will indicate a completely wrong choice, as explained below. Notice that the appearance of a device can be misleading. (For example, a faulty inductor can be essentially capacitive or resistive; a component part can be mislabeled or unlabeled.)

Incorrect choice of parameter, for the measured DUT, is best avoided by watching for the negative LC indicator (below the LC display). If this light is on, when the DISPLAY is VALUE or BIN, the principal parameter (L or C) that has been selected is incorrect. If Ls/Q has been selected, try one of the other 4 selections; and vice versa. (Negative LC indication when the DISPLAY is $\Delta C/\Delta L$ means that the percent difference is negative, i.e., the measured value is less than the stored nominal value.)

Equivalent Series R for Capacitors. The total loss of a capacitor can be expressed in several ways, including D and "ESR", which stands for equivalent series resistance. To

obtain ESR, one can measure directly; push the Cs/Rs parameter key.

"Equivalent series resistance" is larger than the actual resistance of the wire leads and foils that are physically in series with the heart of a capacitor. ESR includes also the effect of dielectric loss. Generally, measured ESR is closer to actual series resistance for capacitors with lower reactance (larger capacitance and/or higher test frequency).

Series and Parallel Equivalent Circuits. Figure 3-10. An impedance that is neither pure reactance nor a pure resistance can be represented at any specific freq uency by either a series or a parallel combination of resistance and reactance. Keeping this concept in mind will be valuable in operation of the instrument and interpreting its measurements. The values of resistance and reactance used in the equivalent circuit depend on whether a series or parallel combination is used. The equivalent circuits are shown in the accompanying figure, together with useful equations relating them. Notice that the Oigibridge displays measurement results directly in terms of series parameters if you select Ls/Q, Cs/O, or Cs/Rs; in terms of parallel parameters if you select Cp/Gp.

If you need Lp, calculate it from measured Ls and D or Q, using the formulas given in the figure. Notice that the instrument will make a valid measurement of Gp for an inductor when the selected parameter is Cp/Gp, even though the negative LC indicator is lighted. (The measured value of negative capacitance is correct, but requires interpretation.)

3.5.2 Measurement Modes.

Continuous. Select CONT for automatically repeating measurements, at one of 2 rates (approximately 2 or 4 per second) as you choose SLOW or FAST. The displays will NOT be held after the OUT is removed or changed. Although there may be some annoyance due to changeability of the least significant digits in the displays, this mode provides a rapidly updated "current" measurement automatically. So it is the normal mode.

Single. Select SINGLE for a measurement to be made with each depression of the START button. The resulting LC and QORG displays are held until a subsequent measurement is made, regardless of changing the OUT. This mode is suitable for many kinds of "production" testing programs.

Average. Select AVERAGE for a string of 10 measurements to be made after each depression of the START button. A running average is displayed; that is, each time a measurement is completed, the LC and QORG displays are updated to be the average of all measurements made since *"start".* After the 1Oth measurement (5 s after "start", if selected RATE is SLOW), the displays are held, as described above. This mode provides smoothing of any possible "noise" or slight variation from one measurement to another theoretically identical measurement, in a particularly convenient way.

Resistance and Inductance

$$
Z = R_s + j\omega L_s
$$

\n
$$
Z = \frac{j\omega L_p R_p}{R_p + j\omega L_p}
$$

\n
$$
Q = \frac{1}{D}
$$

\n
$$
Q = \frac{\omega L_s}{R_s}
$$

\n
$$
Q = \frac{R_p}{\omega L_p}
$$

\n
$$
L_s = \frac{Q^2}{1 + Q^2} L_p
$$

\n
$$
L_s = \frac{1}{1 + Q^2} L_p
$$

\n
$$
L_p = (1 + D^2) L_s
$$

\n
$$
R_s = \frac{1}{1 + Q^2} R_p
$$

\n
$$
R_p = (1 + Q^2) R_s
$$

\n
$$
R_s = \frac{\omega L_s}{Q}
$$

\n
$$
R_p = Q\omega L_p
$$

\n
$$
R_p = \frac{1}{Q_p}
$$

Resistance and Capacitance

$$
Z = R_{s} + \frac{1}{j\omega C_{s}} \quad Z = \frac{R_{p}}{1 + j\omega R_{p}C_{p}} \quad Z = \frac{D^{2}R_{p} + 1/(j\omega C_{p})}{1 + D^{2}}
$$

$$
D = \frac{1}{Q} \qquad D = \omega R_{s}C_{s} \qquad D = \frac{1}{\omega R_{p}C_{p}}
$$

$$
C_{s} = (1 + D^{2}) C_{p} \qquad C_{p} = \frac{1}{1 + D^{2}} C_{s}
$$

$$
R_{s} = \frac{D^{2}}{1 + D^{2}} R_{p} \qquad R_{p} = \frac{1 + D^{2}}{D^{2}} R_{s}
$$

$$
R_{s} = \frac{D}{\omega C_{s}} \qquad R_{p} = \frac{1}{\omega C_{p}D} \qquad R_{p} = \frac{1}{G_{p}}
$$

Figure 3-10. Equivalent circuits for a lossy inductor and a lossy capacitor.

3-12 OPERATION

3.6 LIMITS, BINS, GO/NO-GO, AND PERCENT DELTAS. 3.6.1 Introduction.

If a group of similar OUT's are to be measured, it is often convenient to use the limit-comparison capability of the Digibridge to categorize the parts. This can be done in lieu of or in addition to recording the measured value of each part. For example, the instrument can be used to sort a group of nominally 2.2-pF capacitors into bins of 2%, 5%, 10%, 20%, lossy rejects, and other rejects. Or it can assign OUTs to bins of (for example) a 5% series such as 1.8, 2.0, 2.2, 2.4, 2.7 pF, etc. The bin assignments can be displayed, for guidance in hand sorting, or (with the interface option) output automatically to a handler for mechanized sorting.

Up to 8 regular bins are provided for, in addition to a bin for QORG rejects and a bin for all other rejects; total = 10 bins. To set up the desired categories, use the 16 limits-entry keys in the left rear part of the keyboard, as described below.

Limits are normally entered in pairs (defining the upper and lower limits of a bin), in the form of "nominal value" and "percent" above and below that nominal. If only one "percent" value is entered for a bin, the limit pair is symmetrical (such as ±2%). Two "percent" values must be

entered, the higher one first, to set up a non-symmetrial pair of limits. Any overlapping portion of 2 bins is automatically assigned to the lower-numbered bin.

For simple GO/NO-GO testing, set up a QORG limit and 1 regular bin. Entry of limits in additional bins will define additional GO conditions. Be sure the unused bins are closed. (Bins ¹ ... ⁸ are initially closed, at power-up.)

3.6.2 Limit Entry Methods. Figures 3-11,3-12.

The figures illustrate 2 basic methods of limit entry: nested and sequential. Nested limits are the natural choice for sorting by tolerance around a single nominal value. The lower numbered bins must be narrower than the higher numbered ones. Symmetrical limit pairs are shown; but unsymmetrical ones are possible. (For example, range AB could be assigned to bin 3 and range FG to bin 4 by use of unsymmetrical limit pairs in these bins.)

Sequential limits, on the other hand, are the natural choice for sorting by nominal value. Any overlap is assigned to the lower numbered bin; any gap between bins defaults to bin 9. The usual method of entry uses a redefined nominal value for each bin, with a symmetrical pair of limits. If it is necessary to define bins without overlap or gaps, use a single nominal value and unsymmetrical limit

Figure 3-11. Nested limits. A single nominal value Y is used and all limit pairs are symmetrical in this basic plan.

Figure 3-12. Sequential limits. A different nominal value is entered for each bin, and all limit pairs are symmetrical except for the unsymmetrical pair shown for example in bin 5.

pairs. It is possible to set up one or more tighter-tolerance bins within each member of a sequence.

3.6.3 Limit Entry Procedure.

a. With DISPLAY key, select VALUE.

b. With FUNCTION key, select ENTER.

c. With parameter key Ls/Q, Cs/D, Cs/Rs, or Cp/Gp (by repeat keying if necessary) select convenient units as shown in the display.

d. Enter the desired QDRG limit by keying:

 $[X]$ [=] [BIN] [0],

in which X represents 1 to 5 numerical keys and (optionally) the decimal-point key, depressed in sequence. Confirmation is shown on the QDRG display, up to 4 significant digits.

e. Enter a nominal value for limits by keying:

 $[Y]$ [=] [NOM VALUE],

in which Y represents 1 to 5 numerical keys and (optionally) the decimal-point key, depressed in sequence. Confirmation is shown on the LC display. Notice that the units were seIected in step c.

f. For a symmetrical pair of limits (centered on the nominal value just entered), enter one percentage, by keying:

 $[S]$ $[\%]$ $[=]$ $[BIN]$ $[Z]$;

in which S represents 1 to 5 numerical keys and (optionally) the decimal-point key, depressed in sequence, forming a number not exceeding 100.00; and Z represents one key for the chosen bin: 1,2,3,4,5,6,7, or 8. Confirmation is shown, upper limit on the LC display, lower limit (4 significant digits) on the QDRG display. Notice that these displays are actual L or C values, not percentages.

g. For an unsymmetrical pair of limits, similarly, key in: $[H][%]$ $[-] [L] [%]$ $[=] [BIN] [Z]$;

in which H represents a number not exceeding 10000 and L a number not exceeding 100.00. Both H and L (or neither) may have a negative-sign prefix; but H must always yield a higher limit (absolute value) than L.

h. To enter another pair of limits based on the established nominal value, repeat step f or g, choosing another bin number.

i. To enter another pair of limits based on a different nominal value, repeat step e and then step f or g, similarly.

j. To change the limits in any of the 8 bins, reenter the pair, as above.

k. To close a bin that has limits entered in it, repeat step f with zero for S. Confirmation is shown by 2 identical numbers appearing in the LC and QDRG displays.

I. To resume operation of the Digibridge, using the limits entered as above, press the DISPLAY key. The display will be either measured VALUE, or BIN, whichever you select. In either case, if you have the Interface Option, the available output data are not limited to the display selection.

3.6.4 Example - Entry of Sequential Limits.

To enter a set of sequential limits, operate the keyboard as described below for the following capacitor sorting example: $D < .005$, C = 91, 100, 110, 120, 130 pF (the standard 5% series).

- a. With DISPLAY key, select VALUE.
- b. With FUNCTION key, select ENTER.
- c. With parameter key Cs/D, select LC units: pF.
- d. Enter D limit: [.] [0] [0] [5] [=] [BIN] [0].
- e. Enter nominal LC value: [9] [1] [=] [NOM VALUE].
- f. Set bin 1 limits: $[5] [%] [-] [BIN] [1]$.
- g. Redefine nominal: $[1] [0] [0]$ $[=] [NOM VALUE]$.
- h. Set bin 2 limits: [5] [%] [=] [BIN] [2].
- i. Redefine nominal: $[1] [1] [0]$ $[=]$ $[NOM VALUE]$.
- j. Set bin 3 limits: $[5] [%] [-] [BIN] [3]$.
- k. Redefine nominal: $[1] [2] [0]$ $[=]$ [NOM VALUE].
- I. Set bin 4 limits: [5] [%] [=] [BIN] [4].
- m. Redefine nominal: $[1] [3] [0]$ $[=]$ [NOM VALUE].
- n. Set bin 5 limits: [5] [%] [=] [BIN] [5].
- o. Close bin 6 (if open): $[0]$ $[\%]$ $[=]$ $[BIN]$ $[6]$.
- p. Close bins 7 and 8, similarly (if used before).

3.6.5 Entries in General.

For additional detail, refer to the condensed instructions on the reference card under the Oigibridge, and to the following notes.

Bin 0. The limit entered in bin 0 is always QD RG. For D, Rs, or Gp, it is an upper limit. For Q only, it is a lower limit.

Unsymmetrical Limit Pairs. Enter 2 percentages for the bin. One or both may be $+$ (unspecified sign) or $-$. Enter first the one that yields the larger absolute value of LC.

Unused Bins. Initially, at power-up, bins 1 8 are closed so that unused ones can be ignored. Every unused bin that has previously been used (except 9) must be closed by entering 0%, as in the above examples. Once closed, it will stay closed until non-zero percent limits are inserted.

Allowable Limits. Positive limits up to 10 000%, negative limits down to -100%, maximum of 5 significant figures (for example: 38.671%).

Bin Order. Optional except for nested bins; be sure the narrower limit pairs go into lower numbered bins (because all overlap goes to the lower bin).

Inhibiting Comparisons. To inhibit QDRG comparisons, set bin 0 to zero. To inhibit all comparisons, set NOM VALUE to zero. (Then GO/NO-GO indicators stay off.) Subsequent setting of NOM VALUE to any number except zero enables all comparisons as previously set up.

When POWER is switched ON, "nominal value" is initialized at zero. (Comparisons are inhibited.)

Changing Entries. Enter new value(s) – or a zero – to delete obsolete or erroneous nominal value or bin limits. Do not attempt to change or enter a single separate limit in a bin; any single percentage entered for a bin will be inter-
preted as a symmetrical pair of limits. Changing "nominal value" does not change any limits, but does determine the base for subsequent limit entries for specific bins.

Sorting Resistors. Do not attempt to sort resistors into several bins, because there are only 2 possible categories for QDRG sorting. There are other Digibridge models well suited to measuring and sorting resistors.

3.6.6 Verification of Nominal and Limit Values.

While the DISPLAY selection is ENTRY, the exact values entered into the Digibridge can be seen by either of 2 methods, as follows.

During the Entry Process. A confirming display is automatically provided immediately after the final keystroke of each entry step. For example, after the [NOM VALUE] keystroke, the entered value appears on the LC display. After the [BIN] and number keystrokes, the actual limits of LC value (not percentages) appear across the full display area: upper limit on the regular LC display, lower limit (minus the least significant digit) in the regular QDRG display area. For bin 0, the QDRG limit appears in the QDRG area.

Upon Demand. To see the current "nominal value," depress the [NOM VALUE] key (while the ENTRY light is lit). To see the limits in any particular bin (or to verify that it has been closed), depress [BIN] and the desired number, similarly. Displays selected in this way are limited by the units that are shown on the panel.

However, any "nominal values" previous to the current one are lost and cannot be displayed (unless entered again). Bin limits are not lost until replaced by new entries in the particular bin; but they are lost when POWER is switched OFF.

3.6.7 Percent-Difference $-\Delta C/\Delta L$.

This Digibridge will display (if desired) percent-difference of the measured L or C from a previously stored reference. (The other 2 alternative displays are measured value or bin number.) There are 2 ways to store the reference for percentdifference (delta) measurements: measured-value storage and keyed-number storage, as described below.

Measured- Value Storage. To store the current L or C measurement as reference for percent-difference measurements, follow this procedure.

- a. Set FUNCTION to MEASURE.
- b. Set MEASURE MODE to AVERAGE.
- c. Set DISPLAY to VALUE.

d. Press START button; wait for complete measurement.

e. Press [NOM VALUE] key.

Keyed-Number Storage. To store any desired value as reference, similarly, follow this procedure.

- a. Set FUNCTION to ENTER.
- b. Enter the desired nominal value through the keyboard.

For example, to enter 15, key in:

 $[1] [5] [-] [NOM VALUE]$.

Percent-Difference Display. To obtain a display of percent-difference (measured value vs stored reference), this is the procedure in brief.

a. Set FUNCTION to MEASURE.

b. Set DISPLAY to Delta C/Delta L ($\Delta C/\Delta L$).

c. Observe that the next measurement(s) is now percentdifference from the stored reference (NOT an absolute value).

3.6.8 Value, $\Delta C/\Delta L$, Bin, and Go/No-Go Displays.

The Digibridge measurement will be displayed in one of three ways: VALUE, $\Delta C/\Delta L$, or BIN (any one for a single measurement). This distinction is unimportant for most measurements, in the continuous mode. But for single or average-mode operation, select the desired display before pushing START. Details follow.

For any of these displays, select MEASURE with the FUNCTION key.

Value. Select VALUE with the DISPLAY key. When measurement is completed, the value will be shown on the LC and QDRG displays.

Percent-Difference. Select Delta C/Delta L ($\Delta C/\Delta L$) with the DISPLAY key. Observe that the next measurement(s) is now percent-difference from the stored reference (NOT an absolute value).

Bin. Select BIN with the DISPLAY key. When measurement is completed, the bin assignment will be shown on the LC display (a single digit), with the following significance:

- $0 = No-Go$ because of Q, D, R, or G limit
- $1 = Go$, bin 1
- $2 = Go$, bin 2
- ... Go, bin 3, 4, 5, 6, 7, or 8, as indicated.
- $9 = No-go by default (suits no other bin).$

GO/NO-GO. If comparison is enabled, by a non-zero entry for "nominal value" (see para 3.6.5), this indication is provided. The DISPLAY selection can be VALUE, $\Delta C/\Delta L$, or BIN. GO means the measurement falls in bin ¹ ... 8; NO-GO means bin 0 or 9.

3.7 BIAS.

WARNING

- Maximum bias voltage is 60 V. Do NOT exceed.
- Bias voltage is present at connectors, probe, test fixtures, and on capacitors under test.
- Capacitors remain charged after measurement.
- Do not leave instrument unattended with bias "on."

To measure capacitors with dc bias voltage applied, use the following procedure.

a. Connect a bias supply via rear-panel connector,

observing polarity, as described in para 2.6. Generally, the external circuit should include switching for both application of bias and discharge of the DUT.

b. Use the EXT BIAS switch on the keyboard to apply bias (ON) and to discharge the DUT (OFF), except as follows. Use of a charge/discharge switch in the external bias circuit is recommended for production-quantity measurements, to avoid unnecessary wear on the EXT BIAS switch.

c. Be sure to orient the DUT correctly (positive terminal to the left in the 1687-9600 test fixture).

d. Operate the bridge in the usual way. Disregard any measurements that may be made by the Digibridge in continuous measurement mode during the charge or discharge transients. Notice that the BlAS ON light indicates the presence of bias voltage; it goes off when the voltage drops to zero even though the EXT BIAS switch may be ON. This indicator will not light if the bias power supply polarity is inverted.

Notice that exceeding the 60-V limit of bias voltage is hazardous to personnel. It is also Iiable to damage the Digibridge.

3.8 OPERATION WITH A HANDLER.

If you have the interface option and have made the system connections to a handler (para 2.7), the essential Digibridge operating procedure is as follows:

a. Enter the bin limits as described above.

b. Select the measurement conditions as desired: MEASUREMENT RATE, MEASUREMENT MODE (SINGLE). (Do NOT change parameter after limits have been entered.)

c. Select either BIN or VALUE DISPLAY for incidental monitoring of measurements while the handler automatically sorts the parts being processed.

CAUTION Be sure Digibridge power is OFF while any connections are made or broken at the IEEE-488 INTERFACE connector or its cable. Otherwise, calibration may be lost.

3.9 SYSTEM CONSIDERATIONS.

These considerations apply only if you have the interface option. (If you do, there will be interface connectors at the rear.)

3.9.1 IEEE-488 Interface Unused.

If there is no system connection to the IEEE-488 INTERFACE connector, be sure to keep the TALK switch set to TALK ONLY.

3.9.2 Talk-Only Use.

This pertains to a relatively simple system, with the Digibridge outputting data to one or more "listen-only" (IEEE-488 compatible) devices such as a printer.

Operate the Digibridge in the usual way (manually). The system may constrain operation in some way. For example, a slow printer will limit the measurement rate because it requires a certain time to print one value before it can accept the next.

3.9.3 Talk/Listen Use.

Observe the REMOTE CONTROL indicator light. If it is lighted, there is no opportunity for manual operation (except entry of limits). The displays may be observed then, but their content is controlled by the system controller, via the IEEE-488 bus.

Entry of Limits. Any remotely controlled systems use involving limit comparisons must be designed for manual entry of limits, as follows.

- a. Be sure the REMOTE CONTROL light is out.
- b. Enter the limits as described in para 3.6.

c. Enable the controller to proceed. (This step may require attention to controls on some other device in the system besides the Digibridge.)

Theory- Section 4

4.1 INTRODUCTION 4-1 4.2 PRINCIPAL FUNCTIONS 4-3 \mathcal{L}^{max}

4.1 INTRODUCTION.

4.1.1 General.

This instrument uses an unusual method of measurement, which is quite different from those used in most impedance meters or bridges. A thorough understanding of this method will be helpful in unusual applications of the instrument and be useful in trouble analysis, in case of a possible malfunction. The following paragraph gives a brief overall description outlining the measurement technique to one familiar with impedance measurement methods. A more detailed description of operation, specific circuitry, and control signals is given later.

4.1.2 Brief Description of the 1687 Digibridge.

This DigibridgeTM uses a new measurement technique, in which a microprocessor calculates the desired impedance parameters for each measurement from a series of 6 or 8 voltage measurements (for FAST and SLOW measurement rates, respectively).* These sub-measurements included quadrature (90 $^{\circ}$) and inverse (180 $^{\circ}$) vector components of the voltage across a standard resistor Rs carrying the same current as Zx. Each of these sub-measurements is meaningless by itself, because the current through Zx is not controlled. But each set of voltage measurements is made in rapid. sequence with the same phase-sensitive detector and analog-to-digital converter. Therefore properly chosen differences between these sub-measurements subtract out fixed offset errors, and ratios between the differences cancel out the value of the common current and the scale factor of the detector-converter.

The quadrature sub-measurements are made by shifting the phase of the test signal, rather than the reference to the phase detector. No precision analog phase shifting or voltage squaring circuitry is required. Correct phase relationships are maintained by generating test signal and reference signals from the same high-frequency source.

There are no critical adjustments in the Oigibridge, thanks to the-measurement technique. The only precision component in this instrument is a quartz-crystal stabilized oscillator. The impedance standard is a stable resistor

(exact value unimportant), but there is no reactance standard. The effective value of the resistance standard is automatically determined each time the Oigibridge is recalibrated. (Notice that the ultimate standards are an external capacitor and the oscillator frequency.) The desired parameters of the OUT are calculated by the microprocessor from the set of sub-measurements, known frequency and test-signal phase, and the recalibration data stored in random-access memory.

The microprocessor also controls the measurement sequence, using programs in the ROM memory and stored keyboard selections. The desired parameters $-$ Ls and Q, Cs and D, Cs and Rs, or Cp and Gp – and the test rate, slow or fast, are selected by keyboard control.

Leading zeroes before the decimal point are bl anked out of the LC display. Such blanked zeroes are designated with the symbol \emptyset in some parts of this manual.

4.1.3 Block Diagram Figure 4-1.

The block diagram shows the microprocessor in the upper center connected by data and address buses to digital circuitry including RAM and ROM memories, and peripheral interface adaptors (P.IAs).

Analog circuitry is shown in the lower right part of the diagram, where Zx is supplied with a test signal at frequency of 1 MHz from a sine-wave generator, driven by a crystal-controlled digital frequency divider circuit. The phase of the test signal is digitally controlled by the microprocessor, which selects 1 of 4 phases (precisely 90° apart) for each the 6 or 8 sub-measurements that provide data to it for a single measurement of the OUT. The frontend amplifier circuit supplies an analog signal that represents 2 impedances alternately: the internal standard, Rs, and the OUT, Zx.

The detector control circuit provides sampling commands. The detector is a dual-slope converter, including an integrator and comparator, which converts each analog submeasurement signal proportionally into a period of time. The dual-slope measurement is converted into a digital number by a counter that is gated by this period.

From this information and criteria selected by the keyboard (or remote control), the microprocessor calculates the LC and QCRG values subsequently displayed.

^{*}Patent applied for.

4.2 PRINCIPAL FUNCTIONS.

4.2.1 Elementary Measurement Circuit. Figure 4-2.

The measurement technique is shown diagrammatically. A sine-wave generator drives current Ix through the OUT Zx and standard resistor Rs in series. An amplifier with gain K produces voltages e_1 and e_2 in sequence, as determined by switching the ground point $-$ these being the voltages across the OUT and the internal resistance standard, respectively. Simple algebra, some of which is shown in the figure, leads to the expression for the "unknown" impedance:

 $Zx = Rs [e_1/e_2]$

Notice that this ratio is complex. Both a magnitude and a loss (or quality) value are automatically calculated from Zx and frequency.

4.2.2 Frequency and Time Source. Figure 4-3.

A necessary standard for accuracy is the frequency of the

test signal. Equally important are the precise generation of 4 phases of the test signal and clocks for the microprocessor. Frequency and timing requirements are implemented by derivation from a single very accurate oscillator, operating at 16 MHz. Digital dividers and logic circuitry provide the many clocks and triggers, as well as driving the sine-wave generator described below.

4.2.3 Sine-Wave Generation. Figure 4-4.

Using an 8-MHz clock, the sine-wave generator produces an 8-step "raw" approximation to a sine wave. This method, with precise timing, minimizes harmonics up through the fifth, so that the raw sine-wave is easily filtered to produce a low-distortion test signal. Phase shifting is accomplished by digital control of the component steps, which are formed using a 3-bit D-type flip-flop and a weighting network of resistors. After filtering, the test signal is applied to the measurement circuit in the probe.

Figure 4-2. Elementary measurement circuit.

Figure 4-3. Elements of the signal generation and timing circuitry.

Figure 4-4. Simplified diagram of test signal generator.

Service and Maintenance-Section 5

WARNING

These servicing instructions are for use by qualified personnel only. To avoid electrical shock, do not perform any servicing, other than that contained in the operating instructions, unless you are qualified to do so.

CAUTIONS

For continued protection against fire hazard, replace fuse only with same type and ratings as shown on rear panel and in parts list.

Service personnel, observe the following precautions whenever you handle a circuit board or integrated circuit in this instrument.

HANDLING PRECAUTIONS FOR ELECTRONIC DEVICES SUBJECT TO DAMAGE BY STATIC ELECTRICITY

Place instrument or system component to be serviced, spare parts in conductive (anti-static) envelopes or carriers, hand tools, etc. on a work surface defined as follows. The work surface, typically a bench top, must be conductive and reliably connected to earth ground through a safety resistance of approximately 250 kilohms to 500 kilohms. Also, for personnel safety, the surface must NOT be metal. (A resistivity of 30 to 300 kilohms per square is suggested.) Avoid placing tools or electrical parts on insulators, such as books, paper, rubber pads, plastic bags, or trays.

Ground the frame of any line-powered equipment, test instruments, lamps, drills, soldering irons, etc., directly to earth ground. Accordingly, (to avoid shorting out the safety resistance) be sure that grounded equipment has rubber feet or other means of insulation from the work surface.

The instrument or system component being serviced should be similarly insulated while grounded through the powercord ground wire, but must be connected to the work surface before, during, and after any disassembly or other procedure in which the line cord is disconnected. (Use a clip lead.)

Excl ude any hand tools and other items that can generate a static charge. (Examples of forbidden items are nonconductive plunger-type solder suckers and rolls of electrical tape.)

Ground yourself reliably, through a resistance, to the work surface; use, for example, a conductive strap or cable with a wrist cuff. The cuff must make electrical contact directly with your skin; do NOT wear it over clothing. (Resistance between skin contact and work surface through a commercially available personnel grounding device is typically in the range of 250 kilohms to 1 megohm.)

If any circuit boards or IC packages are to be stored or transported, enclose them in conductive envelopes and/or carriers. Remove the items from such envelopes only with the above precautions; handle IC packages without touching the contact pins.

Avoid circumstances that are likely to produce static charges, such as wearing clothes of synthetic material, sitting on a plastic-covered or rubber-footed stool (particularly while wearing wool), combing your hair, or making extensive erasures. These circumstances are most significant when the air is dry.

When testing static-sensitive devices, be sure dc power is on before, during, and after application of test signals. Be sure all pertinent voltages have been switched off while boards or components are removed or inserted, whether hard-wired or plug-in.

5.1 CUSTOMER SERVICE.

Our warranty (at the front of this manual) attests the quality of materials and workmanship in our products. If malfunction does occur, our service engineers will assist in any way possible. If the difficulty cannot be eliminated by use of the following service instructions, please write or phone the nearest Gen Rad service facility (see back page), giving full information of the trouble and of steps taken to remedy it. Describe the instrument by name, catalog number, and serial number. (Refer to front and rear panels.)

5.2 INSTRUMENT RETURN.

5.2.1 Returned Material Number.

Before returning an instrument to Gen Rad for service, please ask our nearest office for a "Returned Material" number. Use of this number in correspondence and on a tag tied to the instrument will ensure proper handling and identification. After the initial warranty period, please avoid unnecessary delay by indicating how payment will be made, i.e., send a purchase-order number.

5.2.2 Packaging.

To safeguard your instrument during storage and shipment, please use packaging that is adequate to protect it from damage, i.e., equivalent to the original packaging. Any Gen Rad field office can advise or provide packing material for this purpose. Contract packaging companies in many cities can provide dependable custom packaging on short notice. Here are two recommended packaging methods.

Rubberized Hair. Cover painted surfaces of instrument with protective wrapping paper. Pack instrument securely in strong protective corrugated container (350 Ib/sq in. bursting test), with 2-in. rubberized hair pads placed along all surfaces of the instrument. Insert fillers between pads and container to ensure a snug fit. Mark the box "Delicate Instrument" and seal with strong tape or metal bands.

Excelsior. Cover painted surfaces of instrument with protective wrapping paper. Pack instrument in strong corrugated container (350 Ib/sq in. bursting test), with a layer of excelsior about 6 in. thick packed firmly against all surfaces of the instrument. Mark the box "Delicate Instrument" and seal with strong tape or metal bands.

5.3 REPAIR AND REPLACEMENT OF CIRCUIT BOARDS.

This instruction manual contains sufficient information to guide an experienced and skillful electronic technician in fault analysis and the repair of some circuits in this instrument. If a malfunction is localized to one board (or more) that is not readily repairable, it can be returned to Gen Rad for repair. To save time, we recommend that you obtain a replacement first, as described below, before returning the faulty board.

Exchanges. For economical, prompt replacement of any etched-circuit board, order an exchange board. Its price is considerably less than that of a new one. Place the order through your nearest GenRad repair facility. (Refer to the last page of this manual.) Be sure to request an exchange board and supply the following information:

1. Instrument description: name and catalog and serial numbers. Refer to front and rear panels.

2. Part number of board. Refer to the parts lists in this manual. (The number etched in the foil is generally NOT the part number.)

3. Your purchase order number. This number facilitates billing if the unit is out of warranty and serves to identify the shipment. The repair facility will arrange for the prompt delivery of a replacement.

To prevent damage to the board, return the defective board in the packing supplied with the replacement (or equivalent protection). Please identify the return with the Returned Material (RM) number on the tag supplied with the replacement and ship to the address indicated on the tag.

New Boards. For equally prompt replacement of any etched-circuit board, and for maximum life expectancy, order a new one. Use the same procedure as described above, but request a new board. Please return the defective one to GenRad.

5.4 PERFORMANCE VERIFICATION.

This procedure is recommended for verification that the instrument is performing normally. No other check is generally necessary because this procedure checks operation of nearly all the circuitry. There are very few calibrations or adjustments that could require resetting; and the internal standards are very stable. (However, for a rigorous performance and accuracy check, refer to para 5.5.) The necessary resistors and capacitors are inexpensive and readily obtained. The most accurate ones available should be used; tolerances listed are the "best" commonly catalogued. Refer to Table 5-1.

CAUTION

Be sure the line voltage switch, rear panel, is correctly set for your power line voltage.

Verify performance as follows:

a. Install the 1687-9600 test fixture as described in para 3.2.

b. Set the line voltage switch, connect the power cord, and depress the POWER button.

Table 5-1 RESISTORS AND CAPACITORS

* Equ ivai ents may be su bstitu ted.

Table 5-2 PERFORMANCE VERIFICATION

* Refer to paragraphs headed "Tolerances" and"Insignificant figures," in the accompanying text.

c. Press the MEASURE RATE key as many times as necessary to select SLOW. For DISPLAY, verify that the VALUE light is on. (If necessary, operate the corresponding key.)

d. Perform the open/short calibration as described in para 3.4.2.

e. Press the FUNCTION key as many times as necessary to select MEASURE. For MEASURE MODE, verify that the CONT light is on. (If necessary, operate the corresponding key.)

f. Press parameter key Rs/Cs and verify that anyone of the corresponding units is indicated on the display panel (k Ω or Ω).

g. Set the EXT BIAS slide switch to OFF. Set the TALK switch (rear panel, provided only with the Interface Option) to TALK ONLY.

h. Insert the 1DO-ohm resistor as the device under test or "unknown" component (DUT).

i. Verify that the displays fall on or between the extremes shown in "check number 1" in Table 5-2, if the resistor value is within the tolerance listed above.

j. Similarly make the other checks indicated in this table.

Tolerances. Acceptable performance of the instrument is bracketed by the set of display "extremes" in Table 5-2. These are defined as the nominal (ideal) measurements plusor-minus the sum of the instrument accuracy tolerance and the OUT accuracy tolerance (or slightly more). If the

accuracy of your OUT is different from the recommendation, revise the acceptable "extremes" accordingly. Notice that this performance verification is NOT intended to prove the accuracy of the instrument.

Insignificant figures. The right-hand digit(s) of the display normally flicker and change if they are not significant for the specified accuracy of the instrument. Refer to para 3.3.

5.5 MINIMUM PERFORMANCE STANDARDS.

5.5. 1 General.

This procedure is a more rigorous alternative to the performance verification described above. Precision standards of impedance are required for this procedure, wh ich checks the accuracy as well as the overall performance of the instrument. It will be controlled from the front panel, without disassembly. Table 5-3 lists the recommended standards and associated equipment.

Verify that the instrument meets performance specifications as follows.

Calibration of Standard. The acceptable LC or QDRG readout (min to max range) may have to be modified if the actual (calibrated) value of your standard or its accuracy (either or both) is different from the tabulated value(s). An example is given in the detailed procedure.

Insignificant Digits. The right-hand digit(s) of the display normally may flicker and change if they are not significant

Table 5-3

EQUIPMENT FOR ACCURACY VERIFICATION AND TROUBLE ANALYSIS

* Equivalents may be substituted, if same accuracy is realized.

* * Required for trouble analysis (para 5.8); not required for para 5.5.

#Included in calibration kit 1687-9605.

for the specified accuracy of the instrument, if the MEASURE MODE is CONT. Refer to para 3.3. If this kind of display is confusing, use AVERAGE MEASURE MODE, remembering to initiate measurements with START and to wait 5 seconds for averaging. Refer to para 3.5.

5.5.2 Calibration Setup.

Make the test setup as follows.

a. Regulate the ambient temperature to $23^{\circ} \pm 3^{\circ}$ C.

b. Connect the test fixture to the Digibridge and install the reference-standard adaptor. Refer to para 3.2.

c. Set the EXT BIAS slide switch to OFF. Set the TALK switch (rear panel, provided only with the Interface Option) to TALK ONLY.

d. Set the line voltage switch, connect the power cord, and depress the POWER button, as described in para 3.1. Allow 40 minutes "warmup," for stabilization.

5.5.3 Full Recalibration and Capacitance Checks.

Continuing after the setup procedure above, calibrate the Digibridge with capacitance standards and check accuracy with other capacitance standards as follows. Refer to para 3.4 for details.

a. Calculate this difference:

(certified value of 100 -pF standard) - (0.172 pF) .

b. Set FUNCTION to ENTER.

c. Use normal entry procedure to enter, as nominal, the value determined in step a. For example, if the standard was 100.15 pF, you would key in:

[9] [9] [.] [9] [8] [=] [NOM VALUE].

d. Perform the open/short calibration as described in para 3.4 and summarized here:

- **Set FUNCTION to CAL. Press CAL key. (CAL** indication is now OPEN.)
- Install the precision open-circuit termination; keep hands away.
- Press START and wait 5 s. (CAL changes to SHORT.)
- Install the precision short-circuit termination in place of the open.
- Press START and wait 5 s. (CAL changes to STAND; the LC display becomes 55555.)
- e. Install the GR 1406-0 (100 pF) in place of the short.

f. Initiate the scale calibration process (which erases previous full recalibration of the Digibridge) by pressing these keys in sequence:

[=] [NOM VALUE] [START].

Notice that the LC display goes out after you press NOM VALUE. After START, wait for the STAND indication to go off and the NO-GO light to come on.

- g. Set up the following conditions for measurement: FUNCTION - MEASURE DISPLAY $-\Delta C/\Delta L$ MEASURE RATE - SLOW MEASURE MODE - CONT Parameter $-$ Cs/D.
- h. Verify that the displays are: **LC** display $\%$ = -0.085 (min) to 0.085 (max). QDRG display = .0000 or .0001.

i. Check as follows that the calibration data are properly retained.

- Switch POWER OFF and wait at least 1 minute.
- Switch POWER ON again.
- Repeat steps b, c, g, and h.
- j. Set up the following conditions for measurement:

FUNCTION - MEASURE DISPLAY - VALUE MEASURE RATE - SLOW (initially) MEASURE MODE $-$ CONT (or AVERAGE)* Parameter - Cp/Gp.

k. Install the 1-pF standard (initially) as DUT, replacing the standard used for calibration.

I. Calculate the effective value of the DUT (explained in para 3.4.4) as follows:

(certified intrinsic C of standard) $-$ (0.172 pF).

m. Refer to Table 5-4 (first line, initially), which gives the range of acceptable display values for nominal effective value of the standard. Mentally correct this range for your particular standard as in the following example. If the

certified capacitance were 1.0027, the effective value would be 0.8307. However, the "extremes" shown in lines 1 and 2 of Table 5-4 are based on a nominal of 1.000 pF; so, for this example, subtract a correction of 0.169 pF. For the first line, then, the acceptable range would be

 $0.961 - 0.169 = 00.792$; to: $1.039 - 0.169 = 00.870$; for the second line, 00.691 to 00.971 pF.

Also, if you are sure the certified value is correct to a particular accuracy (for example, 0.3%), you can "close" or "open" the acceptable extremes accordingly. (Closing them from ± 0.5 % to ± 0.3 %, for a 1-pF nominal, would mean adding .002 to the lower and subtracting .002 from the upper extreme.)

n. Complete the checks indicated in the table, by repeating steps k, I, and m, above, for the capacitance standards and measurement rates tabulated. The LC display must fall on or between the corrected tabulated "extremes" in each line.

5.5.4 Resistance Accuracy Checks.

Continue after the preceding steps, as follows.

a. Install the axial-lead adaptor on the test fixture, replacing the reference standard adaptor. Set the contacts just far enough apart to accept the longest of the precision resistors neatly. The next 5 steps are an open/short calibration for this test-fixture configuration.

b. With FUNCTION key, select CAL.

c. Press the CAL key to select OPEN indication.

d. Keeping hands away from test fixture, press START and wait until CAL indication changes to SHORT (about 5 seconds).

e. Insert a straight piece of bus wire in the test fixture to short-circuit it, without changing the spacing between $+$ and $-$ contacts.

 † A year of aging has been assumed. If your standard's certification is current, or older than 12 months, consider this in the below-mentioned correction.

*The open-circuit capacitance is known to be 0.172 ± .008 pF. The uncertainty of .008 pF is tabulated as percentage of the measurement. ** If the effective value of your capacitance standby is sl ightly different from the nominal value (assu med) or if the standard's accu racy is

different from the typical accuracy, correct the "acceptable extremes" accordingly.

^{*} If a measured value is difficult to read because of a flickering digit, select AVERAGE and press START. (The display will soon settle to a fixed number.)

Table 5-5 R ACCURACY CHECKS

* If the known value of your precision resistor is slightly different from the nominal value (assumed) or if its accuracy is different from the typical standard accuracy (tabulated), correct the "acceptable extremes" accordingly.

Table 5-6 D ACCURACY CHECKS

*Includes allowance for capacitor D of .0001. If capacitor has slightly higher D, increase the acceptable "extremes" accordingly. * *If the known value of R or C is different from the nominal value (assumed) or if its accuracy is different from that tabulated, correct the acceptable "extremes" accordingly.

f. Press START and wait until CAL indication changes to STAND (about 5 seconds). This completes the *openl* short calibration.

g. Select measurement conditions as follows:

FUNCTION - MEASURE DISPLAY - VALUE **MEASURE RATE - SLOW** MEASURE MODE - AVERAGE Parameter - Cs/Rs.

h. Insert the first precision resistor as 0 UT in the test fixture, press START, and verify that the QDRG display falls on or between the acceptable "extremes." Refer to Table 5-5. Continue down the table, similarly checking accuracy at each line.

5.5.5 Dissipation-Factor Accuracy Checks.

Continue after the preceding steps, as follows.

a. Insert, as OUT, a series combination of precision resistor and mica capacitor, values listed in the first line of Table 5-6. Make the *RiC* connection in midair by crossing component leads and clamping them with a small alligator clip or paper clip. Keep the length of the total circuit path through the OUT short; and avoid adding unnecessary stray capacitance.

b. Select measurement conditions:

Parameter - Cs/D.

c. Press START. Verify that the averaged QDRG display falls on or between the acceptable "extremes" tabulated. Continue down the table, checking accuracy at each line.

5.5.6 Conductance Accuracy Checks.

Continue after the preceding steps, as follows.

a. Insert, as OUT, the precision resistor listed in the first line of Table 5-7.

b. Select measurement conditions:

Parameter - Cp/Gp.

c. Press START. Verify that the averaged QORG display falls on or between the acceptable "extremes" given in the table. Continue down the table to complete the G accuracy checks.

5.5.7 Limits-Entry and Keyboard Checks.

A variable capacitor is used in the following procedure to check the limit comparison functions of the Oigibridge. If your capacitor is not the recommended type, it must be calibrated (using the Oigibridge if desired) so that the C values specified in the accompanying table can be readily set within ±O.3 pF; use binding-post adaptors.

a. Connect the variable capacitor as 0 UT, using 2 plain wire leads from capacitor binding posts to test-fixture adaptor. Use reasonably short leads, well spaced apart from each other; and position the capacitor where it can be reset and observed without moving the leads or adding hand capacitance to the circuit unnecessarily.

b. Set up the conditions for measurement:

FUNCTION - MEASURE DISPLAY - VALUE **MEASURE RATE - SLOW** MEASURE MODE - CONT Parameter $-$ Cs/D.

*If the value of a standard differs from nominal or if its accuracy is different from that tabulated, correct the "acceptable extremes" accordingly.

c. Set the capacitor so the LC display becomes 100.00 pF. Observe the capacitor dial. (Subsequent settings must be made without using the Digibridge in this way.)

d. Change FUNCTION to ENTER. Verify that no digits are displayed for LC or QD RG.

e. Depress in sequence the keys shown by the bracketed symbols (and words) in line 1 of Table 5-8; and verify the displays in the same line.

Table 5-8 LIMIT ENTRY SEQUENCE AND DISPLAYS

Limit-Entry Key Sequence		LC Display	ODRG Display
[1] [0] [0]	$[=]$ [NOM VALUE]	100.00	(blank)
[.] [0] [1]	[BIN] $[-]$ [0]	(blank)	.0100
$[1] [8]$ $[=]$	[BIN] [1]	100.99	99.00
$[2] [8]$ $[=]$	[BIN] [2]	101.99	98.00
[3] [%] [=]	[BIN] [3]	102.99	97.00
$[4] [8]$ $[=]$	[4] [BIN]	103.99	96.00
$[5] [%] [-]$	[BIN] [5]	104.99	95.00
$[6] [%] [-]$	[6] [BIN]	105.99	94.00
$[7] [8]$ $[=]$	[7] [BIN]	106.99	93.00
$[8] [%]$ $[=]$	181 [BIN]	107.99	92.00

f. Repeat step e for each line in the table, in sequence. Each display should appear when the last key in the line is pressed.

g. Change FUNCTION to MEASURE. Verify that the GO light comes on, along with the usual measurement displays.

h. Change DISPLAY to BIN. Verify that the GO light is on, the LC display is simply 1, and the QDRG display is blank.

i. Refer to Table 5-9. Notice that the last line is now represented by the test setup. Reset the variable capacitor and verify the corresponding displays for each line of the table.

j. With conditions unchanged since last line of the table, introduce loss by touching the terminals of the DUT with your fingers. Verify that the displays change from 1, GO to 0, NO-GO. Remove the "finger" loss; and the displays should reutrn to 1, GO.

k. Inhibit limit comparison by setting nominal value to zero as follows:

> FUNCTION - ENTER [0] [=] [NOM VALUE].

Table 5-9 BIN AND GO/NO-GO CHECKS

I. Verify that the LC display is .00000 and the QDRG display is blank.

m. Set up these conditions.

FUNCTION - MEASURE

 $DISPLAY - BIN.$

There should be no indication of measured value, bin number, or GO/NO-GO, at this step.

n. Change FUNCTION to ENTER.

o. Press parameter key Ls/Q and verify that the units display shows Q , μ H. Similarly check other parameter keys as follows.

p. Press Cs/D; verify: D, pF.

q. Press Cs/Rs three times; verify: $k\Omega$, pF and Ω , pF.

r. Press Cp/Gp three times; verify mS, pF and μ S, pF.

s. Switch the POWER OFF.

This completes the verification that your Digibridge meets or exceeds the minimum performance standards delineated in the specifications.

5.6 DISASSEMBLY AND ACCESS.

WARNING

If dissassembly or servicing is necessary, it should be performed only by qualified personnel familiar with the electrical shock hazards inherent to the high-voltage circuits inside the cabinet. Service personnel, observe the handling precautions given at the front of this section, page 5-1.

5.6.1 Instrument Disassembly. Figures 5-1 through 5-6.

Use the following procedure for access to replaceable parts and contact points used in trouble analysis.

a. Disconnect the power cord.

b. Remove the top-cover screws from the rear panel of the main chassis. See Figure 6-2. Slide the top cover forward about 6 mm so that its front corners are unhooked. Lift it directly upward (Figure 5-1). Reassembly note: 2 screws, 13 mm long.

The next step, removal of display board, is recommended (though not necessary) before removal of the main circuit board. Having the main board firmly supported is an advantage when the display board is removed or inserted.

c. Remove the 2 support screws, at left and right, that hold the display board to its brackets. (See Figure.) Pull the board directly out of its socket in the main board. Keep the display board in its original (inclined) plane until it is completely free (Figure 5-2). Reassembly note: 2 screws, 6 mm long with washers. Do NOT drop them into the instrument.

d. Remove the ribbon cable (1657-0200) from power supply (at V-J1) and main board (at MB-J5). Notice that the connectors are symmetrical and reversible; and the cable is extra long, for convenience in servicing.

The next step, removal of the power supply, is NOT related to the removal of the main board. Either can be left in place while the other is removed.

e. Remove the 4 screws that pass vertically through the 4 corners of the power supply into the main chassis. Lift the power supply slightly and move it back carefully while disengaging the POWER pushbutton extension from its hole in the front panel (Figure 5-3). Reassembly note: 4 screws, 8 mm long.

f. Remove the interface option, if you have one, after

Figure 5-1. Removal of top cover. Items 1 and 3 are screws that hold the display board. Item 2 is ribbon cable 1657-0200 that connects power supply to main board.

removing the 2 large screws with resilient washers in the rear panel. (If the panel held by these screws is blank, leave it in place.) Reassembly note: align board edges carefully with connector and guide that are inside of instrument, while pushing interface option into position.

g. After disconnecting the ribbon cable, provide a convenient "upsidedown" support by reinstalling the top cover, temporarily. Turn the instrument, bottom up.

h. Remove 4 screws from the bottom shell, one near each rubber foot. Lift the instruction card and its retaining pan free. Slide the bottom shell back (or forward), free of the main chassis (Figure 5-4). Reassembly notes: be sure to enfold the pliable dirt seals at left and right sides of main chassis as you start to slide bottom shell onto main chassis; use 4 screws, 9 mm long.

i. Remove 14 screws from positions shown in Figure 5-5 as A, B, and C, to free the main board. Remove the shield, which was held by screws C. Reaching through the access hole at J8 (probe cable connector), and using one hand at the rear edge of the main board, lift the front edge until J8 escapes above the chassis front lip. Lift rear edge until J7 (bias connector) touches rear lip. Rotate the board ccw, sliding J7 over the chassis right side lip until J7 escapes. See Figure 5-6. Rotate cw to restore the original angle (J7 above chassis rear lip). Move the main board toward the rear until J7 protrudes about 1 cm (3/8 in.). Lift mainboard front edge so keyboard assembly can escape. Slide the board forward and up until the display board (if still attached) is entirely free from the chassis.

Reassembly note: return washers (if any) to original positions; screws at A are 6 mm, B are 8 mm and C are 16 mm long. Be sure that hardware makes circuit contact only in those places where it did originally.

j. To remove the keyboard module, remove the 4 screws at E and carefully pull the module directly away from the main board. Reassembly note: be very careful not to bend pins when plugging the keyboard-module connectors into their main-board sockets. Reassembly note: 4 small screws with lockwashers.

Figure 5-2. Removal of the display board.

Figure 5-3. Removal of the power supply. The ribbon cable must be disconnected first. The display board can be left in place, but has been removed in this picture.

Figure 5-4. Removal of the bottom shell. The top cover has been temporarily installed as a support.

Figure 5-6. Removal of the MB board. The ribbon cable must be disconnected first. Prior removal of the display board also is highly recommended. Because the board is partially enclosed by the main chassis, some motions are necessary, as described in the text.

Figure 5-5. Locations of screws on the main board, bottom view. Screws at A, B, and C hold the board to the chassis. Screws at 0 hold brackets for display board; at E, the keyboard assembly.

Locations of principal interior parts and points of interest for trouble analysis are shown in the accompanying pictures.

On the main board, notice that the analog circuitry is placed along the front (forward of the display-board connector) and along the right-hand edge. Most of this board supports digital circuitry.

For a more complete guide to parts location, refer to Table 5-10. This lists the principal parts of the main board and indicates where each one is shown on the board layout and the schematic diagrams. The alphanumerics such as B4 or C6 are coordinates on the indicated figures in Section 6. The vertical coordinates are A to E (top to bottom); the horizontal coordinates are 1 to 8 (left to right).

5.6.2 Access. Figures 5-7, 5-8, 5-9. 5.6.3 Reference Designations.

Refer to Section 6 for an explanation of these designations. For example, V-Tl designates transformer number one in the power supply (V) assembly. DB-U52 is integrated circuit number 52 on the DB board, which is the display board.

5.6.4 Removal of Multiple-Pin Packages.

Use caution when removing a plug-in integrated-circuit or other multiple-pin part, not to bend pins nor stress the circuit board. Withdraw the part straight away from the board. Unless an IC is known NOT to be a type (such as MOS) that is subject to damage by static electricity, place it immediately on a conductive pad (pins in the pad) or into a conductive envelope.

Table 5-10 DO NOT attempt to remove a soldered-in IC package MAIN-BOARD PARTS LOCATIONS THE UNLESS YOU have the proper equipment and skills to do so without damage. If in doubt, return the board to GenRad.

The 1687-9600 Test Fixture can be disassembled for

cleaning or repair. Use this procedure.
a. Disconnect and remove any test-fixture adaptor and/or probe-and-cable assembly that may be attached. Turn the fixture upside down.

b. Remove the 4 screws (A) through the rubber feet. Slide the bottom shell off as shown. Reassembly note: 4 screws, 1 cm long.

c. Remove 4 screws (B) at corners of circuit board
1687-4730. Lift the board out. Reassembly note: position so that tab of shield between $+$ and $-$ contacts fits into slot in guide plate; start 4 screws (6 mm, with washers) but do not tighten; plug probe into position and insert 2 typical
radial-lead DUTs (one in each slot, leads well separated); clamp the probe while board is positioned so that DUT leads are centered in their guide slots; tighten the 4 screws; remove DUTs and probe.

d. To remove 2 front contacts (P/N 1686-1940) for cleaning, use a hexagonal wrench (2.38 mm, 3/32 in.) to remove 2 screws (C) per contact. Reassembly note: gap between contacts should not exceed 0.24 mm (.009 in., or the thickness of 3 layers of typing paper); and contacts must press against each other (insulated by tiny dielectric spacers attached near each end of slot) so that a wire of 0.64 mm diameter (AWG 22, .025 in.) can be withdrawn from between them with a force of 1 (minimum) to 2
(maximum) newtons (100 to 200 grams). Tighten the hexdrive screws with a torque of 1.3 to 1.4 newton-meters

e. If necessary, remove the 2 remaining contacts as in the previous step. Reassembly note: align the contacts so that the surfaces that will press against the DUT leads are collinear (so that the guide plate can be positioned with its slots matching the gaps in BOTH contact pairs); tighten hexdrive screws as specified above.

5.6.6 Probe and Cable Assembly.

Do NOT attempt to disassemble the probe (except for removal of the probe nose). Return the assembly to GenRad ·See Figure 6-4 for physical location. if repair is necessary. Replacements (spares) are readily • ·See indicated figure in Section ⁶ for location on schematic available.

Figure 5-7. Main or MB board, top view. Important points for servicing are indicated. For more detail, refer to the accompanying table and the board layout shown in Section 6.

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Figure 5-8. Power supply (V assembly) and display (DB) board, shown in the instrument with the top cover off.

5.7 PERIODIC MAINTENANCE.

5.7.1 Care of the Test Fixture.

About once a year (more or less depending on usage) the test fixture and its axial-lead adaptors should be inspected and cleaned as follows:

a. Clean the contact surfaces and blades of the axial-lead adaptors with isopropyl alcohol. Rub with a cotton swab (Q-tip). Remove any remaining liquid alcohol by blowing with the breath and remove any remaining cotton fibers, with tweezers.

b. Disassemble the test fixture as far as 5.6.5 step c (board removal) or, if it seems necessary, 5.6.5 step d (removal of front contacts) for access.

c. Clean and check the 4 contact strips. Use a card wet with isopropyl alcohol for cleaning. Hold the board at an angle so that any drip falls away from the circuits.

CAUTION

Do NOT scrape with a metal tool. Do NOT damage the tiny dielectric spacer (near one end of each contact surface).

For best results and minimum maintenance effort, the operator must remove any obvious dirt from leads of DUTs before inserting them into the test fixture. Its contacts will wipe through a film of wax, but they can become clogged and ineffectual if the operator is careless about cleanliness.

5.7.2 Care of the Display Panel.

Use caution when cleaning the display window, not to scratch it nor to get cleaning substances into the instrument. Use soft cloth or a ball of absorbent cotton, moistened with a mild glass cleaner, such as "Windex" (Drackett Products Co., Cincinnati, Ohio). DO NOT use a paper towel; do NOT use enough liquid to drip or run.

If it should be necessary to place marks on the window, use paper-based masking tape (NOT any kind of marking pen, which could be abrasive or react chemically with the plastic). To minimize retention of any gummy residue, remove the tape within 2 weeks.

Figure 5-9. Interface option assembly 1658-4020, including the interface option board (lOB) 1658-4720.

Figure 5-10. An early step in disassembling the test fixture. Screws A pass through the feet and hold the bottom shell. Screws B hold the circuit board.

Figure 5-11. The test fixture further disassembled, showing the circuit board removed. Screws C hold 2 of the contacts and a similar set hold the other 2.

5.8 TROUBLE ANALYSIS.

5.8.1 General.

CAUTION

Only well qualified personnel should attempt trouble analysis. Be sure power is OFF during disassembly and setting up for tests. Carefully observe the HANDLING PRECAUTIONS given at the beginning of Section 5.

Resources. Refer to Section 4 for a good understanding of the theory of operation. The block diagrams and discussion there provide necessary background, which can generally save time in trouble analysis. Refer to Section 6 for hardware details: circuit layouts, schematic diagrams, and parts lists.

Abnormal digital signal levels. Most digital signal levels in this instrument are normally near zero (logic low), about +3.5 to +5 V (logic high), or rapidly switching between these states. Failure of a digital source often produces a dc voltage of about +2 V on a signal line. Use high-impedance probes in measuring. Use a scope as well as a voltmeter, because an average of 2 V may be normal for a digital signal that has a duty cycle near 50%.

Duplicated circuits and resistor networks. Some circuits, as in the display board for example, are duplicated several times. The ICs can usually be exchanged between a faulty circuit and a functional one, to identify a "bad" IC. Notice, also, that the resistor networks DB-Z2 ... DB-Zl0 are simply compact packages of $220-\Omega$ resistors. If one resistor is open, it is not necessary to replace the entire package. Use a 5% resistor. There are also other resistor networks that can be repaired similarly.

Circuit board replacement. Refer to para 5.3 for recommended procedures to obtain replacements.

Telltale symptoms. Scan the following group of symptoms for a preliminary analysis of trouble and suggestions for more detailed procedures, if applicable.

Display. A perpetually blank digit or decimal point may be caused by a fault in the directly associated circuit on the display board. (Refer to comments above.)

Reactance Error. If Land C measurements are inaccurate, the test signal source may be at fault. In checking it, as in the following paragraph, verify that the frequency is within

±0.01% of 1.000 MHz, as specified. (See front of manual.)

Test Signal. To check performance of the test-signal source, use a scope to look at the open-circuit signal at the + terminal of the probe nose. (Be sure there is no OUT.) The signal should be an undistorted sine wave at 1 MHz, amplitude about 0.30 V pk-pk (±15%). If this is correct, skip over para 5.8.4.

Analog Front End. To check the entire analog front end, verify that the signal on the main board at the rear end of C38 (or at MB-U19 pin 6) has the characteristic sawtooth waveform illustrated in para 5.8.5, while the instrument is measuring a OUT. (The size of each individual tooth in the waveform depends on the DUT.) If this waveform is present, for all parameters (Ls/Q, Cs/D, Cs/Rs, Cp/Gp), then skip to para 5.8.7.

Access. Except for the "test signal" check described above, trouble analysis can best be done with the main board and display board assembly sitting on a nonconducting pad, and connected by its regular cable to the Digibridge power supply. The shield (see Figure 5-5) should be set aside. The power supply can also be removed from the main chassis, if desired, and set behind the main board.

Active-Low Signal Nomenclature. Occasionally we signify, in a digital signal name, that the implied function is accomplished when the signal is in the low state, i.e., that the signal is "active low." For this purpose, the hyphen and letter -Lare used as a suffix. This suffix also serves to designate "inverse"; for example, if signal END is processed through a logical inverter, the result can be identified as END- L. Notice that it has been common practice to represent the active-low characteristic by a bar or line drawn above the name. If some use of the bar is found in this manual, we regret the inconsistency, please consider it equivalent to the suffix "- L."

Introduction to Detailed Analysis. The following trouble analysis procedures will serve as a guide for localizing a fault to a circuit area. In some cases, a specific component part can be isolated for replacement. In other cases, the problem can be narrowed down only to a circuit board.

Except for the short-cuts indicated above, follow the procedure strictly in the order given, doing the principal steps (a, b, c, d, ...) until ^a failure is found. If so, follow the secondary steps, if any are given at the point of failure (aa, ab, ac ...).

5.8.2 Power Supply.

Check the power supply (V assembly) if there is a massive failure (nothing works) or as a starting procedure in any thorough analysis. Refer to Figure 5-8.

NOTE

If a voltage regulator (U1 , U2, or U3) must be replaced, be sure to spread silicone grease (like Dow Corning compound No.5) on the surface toward the heat sink. For U1, coat both sides of the insulating washer.

a. Check the output voltages, using a digital voltmeter, with ground reference at V-J1 pin 9 (ribbon cable unplugged), as follows:

- Pin $1 = +5$ V. Pin $3 = +5$ V.
- Pin $4 = -8$ V.

b. Make a check similar to step a, with ribbon cable connected, ground reference at right edge of MB board, probing MB-J5 from below the board. (This checks for overload outside the power supply.)

5.8.3 Power-Up Self Checks.

Each time the 1687 Digibridge is powered up, an internal self check routing is automatically performed. Before the instrument can be operated normally, each step in the self check must pass. If any portion fails, normal operation is inhibited and a corresponding error code is displayed. The five different codes, used to indicate particular areas of failure in this instrument, are explained as follows.

11111 1111. The random-access-memory exercise failed. A read/write test is performed, in which each data bit is exercised in every RAM address. Failure of this test hangs the program.

22222 XXXX. The detector/converter half-scale (zero) test has failed. This test checks the dual-slope detector, sampling switches, zener references, phase reversal circuit, and counters. The QDRG display usually indicates zeromeasurement results, which should be between 20 and 32 (decimal). Otherwise, the display indicates the magnitude of the last failure (0 to 127). Failure of this test hangs the program in an endless loop, repeating the dual-slope measurement sequence. Refer to para 5.8.5, step i for pertinent trouble analysis.

33333 XXXX. The front-end test failed. Check carefully that a probe/cable assembly is installed and that it is properly terminated. Either the probe nose or 1687-9600 Test Fixture is a proper termination. If you have a 5-wire user's cable instead (refer to Figure 3-4), there must be a lowimpedance connection, 10 Ω or less, between A and B and another between C and D. This test checks the following circuitry: signal generator, power amplifiers, signal transformers, probe amplifiers, signal switches, probe connec-

- aa. If Trouble is found at step a, check "+5 V'' circuit:
	- At outputs of U1 and U2: +5 V de (regulated).
	- At WT1 (inputs of U1 and U2): +10.8 V de.
	- Across input to diode bridge (yellow-to-yellow): 10 Vrms
- ab. Check "-8 V" circuit:
	- At output of U3: -8 ^V dc (regulated).
	- At input (center terminal) of U3: -13.8 V dc.
	- Across *WTl* to *WT8:* 11.3 V rms.
- ac. Check power-line circuit to primary of transformer T1.

tions. The QDRG display indicates the square of the ratio of actual signal to full scale. This number should be between 0.25 and 1.0. Failure of this test will hang the program in an endless loop, repeating the dual slope measurement. Refer to para 5.8.4 for pertinent trouble analysis.

44444 4444. The dual-slope converter/detector timeout has been invoked; there has been an invalid measurement. This can occur during power-up self check or during any measurement. (An all-4s display flashing alternately with measurement results will indicate an intermittent fault.) A timeout is built into the program for dual slope measurements. If the burst counter or comparator circuitry malfunctions, the program will "time-out." The unsuccessful measurement is then repeated until the result is satisfactory. A timeout will hang the program in a loop as in failure 2 or failure 3. If the 4's error code on the display is flashing with reading, the malfunctions could be marginal or intermittent. Refer to para 5.8.4 step g for pertinent trouble analysis.

55555. This LC display indicates that the calibration locations in memory are locked out. Notice that this indication is not normally a power-up fault indication; this is a status indication in normal calibration sequences. We list it here for completeness. Once the interlock sequence is entered ("=" key, followed by "NOMINAL" key) the $5's$ code will go out, indicating that calibration is enabled. The operator then presses START (when the standard is connected to fixture), to initiate scale calibration. Refer to Full Recalibration, para 3.4.3.

CAL. If FUNCTION is automatically set to CAL at power-up, there has been a loss or change of calibration data stored in random-access memory. A possible cause is low battery voltage. (Life expectancy of battery, at least in dry climate, is 5 to 10 years.) Refer to Table 1-3 for replacement part numbers. Replacement is a repair/service procedure; see para 5.8.8.

5.8.4 Test Signal Source.

This procedure checks the circuitry that generates the test signal. (We proceed backwards, more or less, toward the osciIlator.)

a. Install the 1687-9600 Test Fixture and insert as DUT a 240-pF capacitor.

b. Select conditions as follows. **FUNCTION - MEASURE**

> DISPLAY - VALUE MEASURE RATE - FAST **MEASURE MODE - CONT** Parameter - Cs/D.

c. Using a scope, check signals at "1 MHz SAL GEN," each terminal versus ground. Probe the white- and blackwire terminals of yellow-banded interior cable, slightly rear from Tl and L10, near right edge of board. Verify: sine wave, 5.5 V pk-pk, 0 V dc, 1 MHz, each terminal. If all right, check also at J8, pins 11, 24, with probe cable unplugged; then reconnect cable.

NOTE

If step c is verified, skip to para 5.8.5. The prefix MB- is understood, below. Unless otherwise stated, connect scope-probe ground clip to ground on main board, such as the frame of J8.

d. Check signals at each end of C43 versus ground. (C43 is just forward of L10.) Verify: sine wave, 20 to 24 V pk-pk (20.6 V ideal), 1 MHz, each end.

e. Check signals at either end of R84 and either end of R86. Both are near front corner of board, forward of Q12. pointing toward 012. (If you are probing bottom of board, find signals at bases of 011 and 012.) Verify: slightly irregular sine wave, 1 to 1.2 V pk-pk, 1 MHz, each.

f. Check signal at input to U41, pin 14. (Pin 1 is at left front.) Verify: slightly irregular sine wave, 130 to 160 mV pk-pk, 1 MHz.

g. Connect a counter to vertical-channel output of the scope for use in the remainder of para 5.8.4. Use a lowcapacitance scope probe, to avoid loading down the circuit being checked.

h. Check signal at C8, left end. C8 is just left of trim pot R87. Verify: slightly irregular sine wave, 250 mV pk-pk, 1.3 V dc, frequency 1.0000 MHz \pm ,0001 MHz. If signal is missing, check frequency in any step below, i through I, (at point closer to oscillator), to \pm .01%.

i. Check input signals to U39. (Pin 1 is at right rear.) Verify: at pin 3, pulses, 3.5 V pk-pk (low 0.1 V, high 3.6 V), 2 pulses unevenly spaced in $1-\mu s$ period, counter reading 2 MHz. Verify: at pin 6, similar. Verify: at pin 11, pulses, 3.5 V pk-pk, similar to above except single pulse with cleft in middle, frequency 1 MHz. Verify: at pin 9, square wave with some fine structure at top and bottom, about 3.7 V pk-pk, frequency 8 MHz.

j. Switch POWER OFF. Remove the keyboard module as described in para 5.6.1. Switch POWER ON. (The Digibridge measure rate will now be SLOW instead of FAST; but the following few steps can be done with either rate.)

k. Check output signals from U30. (Pin 1 is at right rear.) Verify all to be digital, approximately 4 V pk-pk, frequencies as follows: pin 11, 1 MHz; pin 12, 2 MHz; pin 13, 4 MHz; pin 14, 8 MHz.

I. Check oscillator output U29 pin 8 (also available at option-board connector J2 pin 27). Verify: 4 V pk-pk, square wave (sinusoidal shape will appear if limited by scope frequency response), low level approximately 0.4 V, frequency 16.000 MHz ±.0016 MHz.

Factory Adjustments. The purpose of 2 obvious adjustments is given for reference.

L10 is set to maximize the signal through T1, with probe/ cable installed (as indicated in step c, above).

R87 is set to make the test-signal level correct (measured indirectly in step c above).

da. Additional information: dc level 5 V. If signal is all right here but missing in step c, defect is probably in T1.

ea. Additional information: dc level-7.5 V. If signal is present at R86 (nearest corner of board), but missing or weak at right-hand lead of C43, Q12 is not functioning. Check for -8 V dc at emitter (pin at left); if all right, replace Q 12. Similarly, if signal is all right at R84 but not at left of C43, and if -8 V dc is found at Q11 emitter (pin at right), replace Q 11.

fa. Additional information: dc level-1.5 V. If U41 input is all right, but step e discrepant, check at U41, pins 7 and 8 for slightly irregular sine wave, 1 to 1.2 V pk-pk, approximately 1.6 V dc, 1 MHz, each. If either is faulty, replace U41.

ia. Additional information: "low" level is 0 V dc. If step i is all right but signal is faulty at C8, check output signals from U39. Verify: at pin 2, 4 V pk-pk, counter reading 2 MHz, (high 4.5 V, low 0.4 V, 2 positive pulses 0.38 μ s apart in 1 - μs period, each pulse 0.12 μs wide, some ringing at low level). Verify at pin 7, similar waveform. Verify: at pin 10, 4 V pk-pk (positive pulse about 0.3 µs wide), frequency 1 MHz. Otherwise, probably fault is in U39.

ka. Additional information: low level is 0.4 V dc. If U30 outputs are all right but U39 inputs are faulty, check through logic gates U31, U32, U35, and inverters U36.

la. Additional information: low level 0.4 V dc. If U29 output is deficient, replace U29.

5.8.5 Analog Front End.

This procedure checks the detector and associated analog circuitry that process the analog measurement signals from the probe, to the point of conversion into digital form. The operating conditions are given above. Continue, after step c of para 5.8.4, as follows. (Notice that the keyboard assembly should be in place; and verify that the MEASURE RATE is FAST.)

a. Check signal SWX, found at the black-wire terminal of the orange-banded cable. (See center of right edge of board; use 20 ms/div sweep on scope. Verify: digital signal, 3 V pk-pk (2.8 to 3.4 V pk-pk).

b. Check signal SWS, found at the adjacent white-wire terminal. Verify: similar to SWX except for timing. (Timing is not important in this procedure; but timing diagrams are given below.)

c. Check voltage at wire tie labeled *"4.9* V" and/or at J8 pin 5. Verify: 4.9 to 5.1 V dc.

d. Be sure that the probe/cable assembly you are using is labeled "0.1 V." This is P/N 1687-9603.

Check the signal on "+" end of OUT in test fixture. Be sure that scope probe ground is on frame of test fixture. Verify: 1-MHz sine wave, with superimposed very fine structure of about 10 mV pk-pk; the sine level jumps between 160 mV pk-pk (between measurements) and 225 mV (during measurement), 0 V dc. (If you want to verify which is which, use SINGLE MEASUREMENT MODE and START.) These levels depend on value of DUT.

e. Remove probe from test fixture and install probe nose. Check signal on "+" probe tip (scope probe ground on Digibridge ground) while DUT is 240-pF capacitor. Verify: signal similar to step d above.

Return to previous setup (DUT in fixture).

f. Check signal DET SIG at wire tie H of brown-banded cable (near right rear corner of board) and/or J8 pin 3. Verify: high-frequency signal jumping at a low rate between distinct levels (45 mV pk-pk, 70 mV pk-pk). Use 20 ms/div sweep rate to see envelope.

g. Check "burst" signal BST at U40 pins 5 and 6. (Pin 1 is at right rear.) Verify: irregular digital signal, 4.7 V pk-pk (low level 0.4 V dc).

aa. Additional information: low level is -2.2 V dc. If SWX is missing, check X-L at U 12 pin 2. (Pin 1 is at left rear.) Verify: irregular slow digital signal, 5 V pk-pk. If this is all right, replace Q6; if not, fault is in the "PIA" U12 or circuitry "behind" it.

ba. If SWS is missing, check S-L at U12 pin 3. Verify: irregular, slow digital signal, 5 V pk-pk. If this is all right, replace Q7; if not, fault is in U 12, or "behind" it.

ea. If checks are verified up through step c, but both d and e fail, fault is in J8 or probe/cable circuit. Check connections and trace signals where possible. Swap the probe/cable if a spare is available. Do NOT disassemble the probe; replace it or return it to GenRad for repair.

If only step d fails, trouble is in test fixture. It can be serviced. If only step e fails, trouble is in probe nose; replace it.

fa. Additional information: if the 1-MHz sine wave is examined, it shows superimposed "noise" of about 10 to 20 m V pk-pk. If step f is the first one in this procedure to fail, fault is probably in probe/cable assembly; replace it.

ga. Notes: Burst duration is 8.3 ms for FAST, 16.8 ms for SLOW; intervals between bursts are variable; number of bursts per measurement is 6 for FAST, 8 for SLOW; signal within each burst is 1-MHz square wave. If 8ST is missing, check the signals that generate it, at U40 pins 2 and 3. Verify: digital signal, amplitude irregular but approximately 3.5 to 4 V pk-pk, pulse rate 1-MHz interrupted irregularly. Also check U40 pin 1 for continuous 8-MHz square wave (also described for U39 pin 9 in previous paragraph).

h. Check signal MSR at U36 pin 6 and/or gate of U2. (Pin 1 of U36 is at right rear.) Verify: digital signal, 5 V pk-pk, easily seen with scope sweep of 20 ms/div.

i. Check signal ahead of dual slope detector at rear end of R48 (at right of 04) and/or 03 drain (right front pin) and 04 drain (right rear pin); and check at U19 pin 2 and/or 02 drain (right rear pin) and 05 drain (right pin). Verify: small-scale digital signal that looks similar to SST but only approximately 10 to 20 mV pk-pk.

j. Check OVFLOWS signal at U33 pin 11. (Pin 1 is at right rear.) Verify: irregular digital signal, 5 V pk-pk.

k. Check signal at gate of 05 (pin toward rear). Use scope sweep of 20 ms/div. Verify: 8 V pk-pk, irregular digital signal.

I. Check signal at heart of dual-slope-integration detector, at U19 pin 6 or rear end of C38 (at left of U19). Verify: characteristic irregular sawtooth waveform as shown in Figure 5-12.

m. Check comparator output at U18 pin 7 (pin 1 is at right) and/or U34 pin 5 (pin 1 is at right rear). Notice that this pulse is difficult to see because of its very short duty cycle. With a vertical scale of 1 V/div and horizontal scale of 50 μs /div., with very high intensity, a fast scope can be triggered to show a faint spike above a very heavy base line.

If a nonfunctional Digibridge has no fault in the analog circuitry (all the preceding checks are passed or, if not, they do not lead to the fault), then the fault is probably in the digital control circuitry. Proceed to the next numbered paragraph.

Factory Adjustment. The purpose of L2 is given for reference. L2 is set to resonance with C59, i.e., to maximize the signal level across itself. However, because a scope probe at L2 can affect tuning, resonance is better monitored at U19 pin 6 or at 03.

ha. Note: low level is 0.2 V. If MSR is faulty, check back through U36 and U20 gates to U12. See also the check on ENDSAMPLE, below. (Para 5.8.6, step d.) ia. Otherwise, isolate trouble to a particular transistor or other part in this circuit.

ja. Note: low level of 0 VFLOWS signal is 0.3 V; fine structure within each burst is square wave with period of 260 µs. If OVFLOWS is faulty, check for presence of BST signal (see above) at U33 pin 2 and U37 pin 2; verify: 5 V pk-pk, low level 0.5 V dc; if present, fault is in counter U37 or U33.

ka. Additional information: rectangular waveform, irregular, high level 0 V dc. If necessary, trace back through 08, 09, U40, At 08 base (pin at right), 0.5 V pk-pk, low level about -8.3 V dc. At 09 emitter (pin at right), 0.2 V pk-pk, low level about 0.5 V dc. At U40 pin 9 (pin 1 is at right rear), 2.5 V pk-pk, low level 0.5 V dc.

la. Notes: The heights of the individual "teeth" depend on the impedance of the DUT. If MEASURE RATE is SLOW instead of FAST, there are 8 "teeth" instead of 6 per measurement. If this waveform is missing, fault is in U19 or associated circuit.

ma. Notes: With 1 μs /div, it appears that the width of CMP pulse is variable, from perhaps 0.1 μ s to 2 μ s, and height about 1 V. (This short pulse occurs only once for every "tooth," maybe 30 times per second.) If you are sure that this pulse is missing, replace U18.

Figure 5-12. Characteristic irregular sawtooth waveform at heart of dual-slope-integration detector. Vertical scale: 0.5 V/div. Horizontal scale: 20 ms/div. Measurement rate: FAST. Device under test: capacitor, 240 pF, $D = 0.003$. Measurement starts at S and finishes as soon after F as required for data to be processed. Scope triggering on largest "tooth" (at T) causes F to appear near middle of screen, for this particular OUT.

Figure 5-13. Timing diagram; one complete measurement cycle; SLOW. If measurement rate is FAST, the shaded areas are omitted (reducing the number of SST bursts from 8 to 6, and the number of "teeth" in the sawtooth from 8 to 6).

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5.8.6 Control Signal Checks. Figures 5-13, 5-14.

If the analog circuitry, as checked above, fails to produce the specified signals $-$ in particular, if the irregular sawtooth signal in the detector is missing $-$ the fault could be in the digital circuitry that controls analog functions. (Some of the preceding analysis does trace back to digital control signals, such as SWS, SWX, BST, MSR, and the components of the test signal.) The following systematic examination of control signals may isolate a fault that was not located by the above analysis.

Examine each control signal, as listed below and compare it with the timing diagram. If any is abnormal, trace back to its source, with the help of schematic and layout diagrams. Check for poor connections or other interface problems; check simple devices (gates, flip-flops, transistors, etc.), if any are involved.

- a. Examine test-signal-phase control signals: PH1 at U36 pin 3. (Pin 1 is at right rear.) PH2 at U31 pin 10. (Probe bottom of board.)
- b. Examine dual-slope detector control signals: BST at U40 pin 5. (Pin 1 is at right rear.) BST-L at U40 pin 6. MSR at U36 pin 6. (Pin 1 is at right rear.)
- c. Examine feedback signals: * CMP at U34 pin 5. (Pin 1 is at right rear.) OVFLOWS at U12 pin 9. (Pin 1 is at left rear.) DMSR-L at U6 pin 9. (Pin 1 is at right front.)
- d. Examine other digital control signals: START at U38 pin 3. (Pin 1 is at right rear.) F (clock) at U36 pin 1 (right rear). 8F-L (clock) at U40 pin 1 (right rear). ENDSAMPLE at U20 pin 1 (right rear).** ISW-L at U40 pin 9. (Pin 1 is at right rear.) ISW at 05 gate (pin at rear.)

This last, ISW, is the converse of ISW-L. ISW is nominally 8 V pk-pk, high at 0 V dc. ISW must go to low state to permit integrator U19 (with capacitor C38) to function at all, i.e., to generate a "sawtooth."

If the digital control signals are all present and valid as far as can be seen with a scope, the digital control circuitry is functional; then the fault is probably in the integrator U19 or associated circuitry, or perhaps in the probe/cable assembly or test fixture, or in the display board.

On the other hand, if a control signal is faulty, and the fault cannot be located in easily repairable circuits $$ specifically, if the fault is traced back to an apparent source in one of the PIAs (U9, U10, U11, U12) $-$ refer to para 5.8.7 below.

5.8.7 Digital Circuitry.

Display Board. A faulty integrated-circuit package can usually be identified by interchanging plug-in component parts of the same type between display channels. Notice that a resistor network need NOT be replaced as a unit; use ordinary resistors. (See para 5.8.1.)

Recommended Procedure. If careful analysis of a faulty instrument, using the preceding information, indicates that the trouble is in the digital circuitry (whether in control, computation, or display decoding), further analysis is beyond the scope of this manual. Return the faulty board (the MB board, if the fault is digital, and not in the display board) or return the instrument for service. Refer to para 5.2 and 5.3.

Special Testing. Because of the very high speed and considerable complexity of the digital circuitry in the MB Board and lOB (Interface Board), it is impossible to analyze trouble there with ordinary test equipment. GenRad production and in-factory service departments make use of fast, versatile automatic test systems (GenRad products). Their efficiency and accuracy are important factors in our recommendation that digital circuit problems be solved by exchanging boards.

5.8.8 Battery Replacement.

If, at power-up, FUNCTION is automatically set to CAL, you probably should replace battery B1. (See power-up self check in para 3.4 and above in 5.8; see part description in Table 1-3.) The procedure is as follows.

a. Remove the main board.

b. Find B1 at left rear corner. Cut its straps. Observe correct polarity, for replacement.

c. Unsolder and remove old battery with care not to overheat.

d. Install the replacement and secure with straps (like the originals) or lacing cord, to safeguard terminals from strain.

e. Solder the terminals, with care not to overheat.

[·]These feedback signals depend on an output from dual-slope comparator U18, and hence on the sawtooth from U19. • * ENDSAMPLE is derived from OVF LOWS, with delays determined by the microprocessor.

Figure 5-14. Timing diagram; one single "SLOW" sawtooth cycle. A half cycle of the analog signal is integrated while BST is logic high (AB). The other half cycle (BC) of the analog signal is omitted from the integration, which follows the slope (AE) that represents zero analog voltage. Integration continues for 16768 samples, to F. Then the voltage at F is converted into a digital number as follows. Slope FG is a constant; so time interval FG is counted, and the count represents the voltage. *OVFLOWS goes logic high at ends of samples 128, 384, ... 16768; that is, at (2N + 1) 128, where N = 0 .•• 65. **OVFLOWS goes low at ends of samples 256, 512, \dots 16640, i.e., (2N) 128, where N = 1,,, 65. D represents delays controlled by the microprocessor, determining particular timing of ENDSAMPLE.

Parts Lists and Diagrams-Section 6

6.1 GENERAL.

This section contains the parts lists, circuit-board layout drawings and schematic diagrams for the instrument. (Section 4 contains functional block diagrams. Section 5 contains photographs of the instrument, identifying various parts.) The heavy lines on schematic diagrams denote the major signal flow.

Reference designation usage is described below.

6.2 REFERENCE DESIGNATIONS.

Each electrical component part on an assembly is identified on equipment and drawings by means of a reference designator comprised of numbers and letters. Component types on an assembly are numbered sequentially, the numbers being preceeded by a letter designation that identifies the component (R for resistor, C for capacitor, etc.). Some of the less obvious designators

are: DS, lamp; Q, transistor; U, integrated circuit; WT, wire tie point; X, J, P, or SO, connector; V, crystal resonator; Z, network.

Each assembly (typically a circuit board) has its own sequence of designators which can be identified by using prefixes, such as A- for the main frame and V- for power supply. Examples: B-R8 designates B board, resistor 8; D-WT2 = D board, wire-tie point 2; CR6 on the V schematic is a shortened form of designator V-CR6 = V board, diode 6. The instrument may contain A-R1, B-R1, C-R1, and D-R1.

6.3 DIAGRAMS.

Generally, each schematic diagram is located on a righthand fold-out page for convenience. The associated layout drawing and parts list are located on the same page, the facing page, or otherwise nearby.

Figure 6-1. Front view, showing replaceable mechanical parts.

Figure 6-2. Rear view, showing replaceable mechanical parts.

6-2 **PARTS & DIAGRAMS**

K

MECHANICAL PARTS LIST

FRONT

 \textcircled{f}

FEDERAL SUPPLY CODE

FOR MANUFACTURERS

From Defense Logistics Agency Microfiche H4-2 S8708-42 GSA-FSS H4-2

Ref FMC Column

in Parts Lists

Code Manufacturer Code Manufacturer Code Manufacturer Code Manufacturer **2013 Moore Line and Markov 1998** (1998) (1998) (1998) (1998) (1998) (1998) (1999) (1998) (1999) (1999) (1999) (1999) (1999) (1999) (1999) (1999) (1999) (1999) (1999) (1999) (1999) (1999) (1999) (1999) (1999) (1999) (1999 06928 Neddain Elctris.,Nashville,TN 372105 24446 GE.Scheenchafy,NY 12201 23600 Eco Festival,CA 92023 Til.,Atteboro,MA 02703
06928 Aladdain Elctris.,Nashville,TN 37210 24446 GE.Scheenchafy,NY 12201 23600 Eco Festival,NY 121 08730 Vemaline Prod.,Franklin Lakes,NJ 07417 30874 IBM.,Armonk,NY 10504 76241 MaureY.,Chicago,1 L 60616 91662 Elco.,Willow Grove,PA 19090 09213 GE.,Buffalo,NY 14220 30985 Permag Magnetics.,Toledo,OH 43609 76381 3 M CO.,St.Paul,MN 55101 91719 General Inst.,Dallas,TX 75220 02000 Color Research Andrea Maria Section 1992
2003 Super Library (1992) 2003 Super Library (1993) 2003 Super Library 15238 ITT.,Lawrence,MA 08142 54297 Assoc Prec Prod.,Huntsville,AL 35805 80740 Beckman Inst.,Fullerton,CA 92634 99934 Renbrandt.,Boston,MA 02118

JANUARY 1978

6·4 PARTS & DIAGRAMS

15476 Digital Equip.,Maynard,Maynard,Maynard,Maynard,Maynard,Maynard,Maynard,Maynard,Maynard,Maynard,Mo 63166
154715 Shure Bros.,Evanston,1 L 60202 80756 Translat,Melville,NY 11746
15476 Motorola, Franklin Pk,IL 60131
1600

File Courtesy of GRWiki.org

Figure 6-3. Main (MB) board, 1687-4700, digital processor, memories, interfaces.

File Courtesy of GRWiki.org

PARTS & DIAGRAMS 6-5

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أو t: \vec{e} en S $\mathbf \omega$ ē 0 $^{\circ}$ a. .-. en $^{\circ}$ -...J -...J 0 ..0 or \leq ϵ t: 고 \vec{c} \mathbf{r} \bf{p} $\bar{\bm{\sigma}}$ $\mathbf c$ Q) 3' a. $\overline{\overline{}}$ ><

 $9-9$ PARTS **P** DIAGRAMS

Figure 6-5. Main (MB) board, 1687-4700, analog circuitry. **PARTS & DIAGRAMS 6-7**

File Courtesy of GRWiki.org

ELECTRICAL PARTS LIST

ANALOG & CONTROL PC BOARD ASH M8 PIN 1681-4100

ELECTRICAL PARTS LIST (cont)

ANALOG & CONTROL PC BOARD ASM M8 PIN 1687-4700

B
ELECTRICAL PARTS LIST (cont)

ANALOG & CONTROL PC BOARD ASH MB PIN 1681-4100

 $\bar{\omega}$

6-8c PARTS & DIAGRAMS

ELECTRICAL PARTS LIST (cont)

ANALOG & CONTROL PC BOARD ASM MB P/N 1687-4700

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PARTS & DIAGRAMS 6-9a

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PARTS & DIAGRAMS 6-9b

Figure 6-6. Main (MB) board, 1687-4700, measurement counter, display driver.

File Courtesy of GRWiki.org

PARTS & DIAGRAMS 6-11

* NOTE: AN OPEN CIRCUIT IN A RESISTOR NETWORK CAN BE REPAIRED BY SHUNTING
AN EXTERNAL RESISTOR ACROSS THE APPROPRIATE TERMINALS.
1657–0810 (each section): 220 $\Omega \pm 5\%$.

6-12a PARTS & DIAGRAMS

Figure 6-8. Display (DB) board, 1658-4715, layout.

6-12b PARTS & DIAGRAMS

File Courtesy of GRWiki.org

PARTS & DIAGRAMS 6-13

6-14a PARTS & DIAGRAMS

Figure 6-10. Keyboard module assembly, 1687-4200.

6-14b **PARTS & DIAGRAMS**

B

Figure 6-10. Keyboard module assembly, 1687-4200.

6-14c PARTS & DIAGRAMS

 \bar{z}

Figure 6-11. Keyboard (KB) circuit board, 1687-4710, layout.

PARTS & DIAGRAMS 6-15a

R

NOTE: THIS ASSEMBLY INCLUDES THE 1658-4720 CIRCUIT BOARD; SEE BELOW.

INTERFACE OPTION PC BOARD IOB P/N 1658-4720

6-16a PARTS & DIAGRAMS

NOTE. ORIENTATION: viewed from parts side. SYMBOLISM: Solid outlines = component parts. Gray circuit pattern = this side only. (a) denotes pin 1 of IC, connector, relay, etc; + end of capacitor; cathode of diode; collector of transistor; and arm or rotor of variable part. PART NUMBER: refer to figure caption.

Figure 6-13. Interface option (IOB) board, 1658-4720, layout.

6-16b PARTS & DIAGRAMS

PARTS & DIAGRAMS 6-17

Figure 6-14. Interface option (IOB) board, 1658-4720, diagram.

File Courtesy of GRWiki.org

NOTE: THIS ASSEMBLY INCLUDES THE 1657-4720 BOARD; SEE BELOW.

P/N 1657-4720

 $\mathcal{L}_{\mathcal{A}}$

NOTE: Output terminals of voltage regulators are denoted by square pads.

NOTE. ORIENTATION: viewed from parts side. SYMBOLISM: Solid outlines = component parts. Gray circuit pattern = this side only.

(\blacksquare) denotes pin 1 of IC, connector, relay, etc; + end of capacitor; cathode of diode; collector of transistor; and arm or rotor of variable part. PART NUMBER: refer to figure caption.

Figure 6-15. Power supply (V) board, 1657-4720, layout.

PARTS & DIAGRAMS 6-19a

RESISTANCE IS IN OHMS, $K=10^3$, $M=10^6$
CAPACITANCE IS IN FARADS, $\mu = 10^{-6}$, $p = 10^{-12}$
VOLTAGES EXPLAINED IN INSTRUCTION BOOK SERVICE NOTES
CAPACITATION VER CONTROL CILITIES FRAME THE TPETEST POINT
COMPLETE REFERENCE

 \bigcirc) GND Ω BOTTOM VIEW

 $U₂$

PARTS & DIAGRAMS 6-19b

TEST FIXTURE PC BOARD ASM PIN 1687-4130

Figure 6-17. Test fixture 1687-9600 (circuit board -4730), diagram.

6-20a PARTS & DIAGRAMS

PROBE CABLE ASM II PIN 1687-4310* (l V)

PIN 1687-4195 PROBE PC BOARD AS"

*Inc1udes the circuit board shown in the accompanying list.

6-20b PARTS & DIAGRAMS

PROBE CABLE ASM I P/N 1687-4300* (0.1 V)

PROBE PC BOARD ASM P/N 1687-4790

*Includes the circuit board shown in the accompanying list.

6-20c PARTS & DIAGRAMS

RESISTOR VALUES IN OHMS, K=10³ OHMS, M=10⁶ OHMS
CAPACITOR VALUES IN MICROFARADS, p=10⁻¹²
<mark>ELELES</mark> FRONT PANEL LEGEND [EEE] REAR PANEL LEGEND SCREWDRIVER ADJUSTMENT .
• P.C. BOARD FINGER CONNECTION OR MALE CONTACT

FEMALE CONTACT - CONTING CONTACTS $-$ SIGNAL FLOW $-$ SIGNAL PATH

(N) NUMBER OF CONNECTIONS TO THE SOURCE

Figure 6-18. High-level probe (1 V) diagram.

PARTS & DIAGRAMS 6-21a

RESISTOR VALUES IN OHMS, K=10³ OHMS, M=10⁶ OHMS
CAPACITOR VALUES IN MICROFARADS, p=10=¹²
<mark>도프프지</mark> FRONT PANEL LEGEND [도프로지] REAR PANEL LEGEND SCREWDRIVER ADJUSTMENT

WT: WIRE THE **O-TP: TEST POINT**

P.C. BOARD FINGER CONNECTION OR MALE CONTACT FEMALE CONTACT - HATING CONTACTS -------------
-- SIGNAL FLOW SIGNAL PATH

(N) NUMBER OF CONNECTIONS TO THE SOURCE

Figure 6-19. Standard probe (0.1 V) diagram.

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$B(X)N$

For

Instruction Manual

Form 1687-0120-B (April 1978) for GR 1687 Megahertz LC Digibridge

This change notice makes a minor change in specifications, adds information, and corrects several typographical errors. Please note the changes listed below and fasten this notice into your manual, at page 2-3, for reference.

page ii Accuracy •.• when the optional I-V probe is used: change from "L: same as above" to:

> L ACCURACY $=$ ±0.05%M $\left[7 + \frac{L}{500 \mu H} + \frac{30 \mu H}{L}\right] \left[1 + 1/Q\right]$

- page iii Power. Change from "48 to 62 Hz." to: 50 to 60 Hz.
- page 1-6 Table 1-3. Column 2, line 2. Change from "SPH-387" to: SPH-386.
- page 2-2 Figure 2-2. At bottom of figure, change from ".635" to: 6.35. Para 2.6, just before step a, insert: 1. To supply the desired dc voltage, well filtered.
2. Current limited at 15 mA to 200 mA (max). Current limited at 15 mA to 200 mA (max).
- page 2-3 Before para 2.8, insert: For timing information, see change notice that should be fastened here.* Before para 2.8.1, insert: Refer to CAUTION on page 3-16.
- page 2-6 Before para 2.9, insert: New para 2.8.5 is provided on the change notice that should be fastened at page 2-3.*
- page 2-8 Table 2-5 line 11, under "pF, Picofarads", insert: (space)%, $\Delta\%$.
- page 3-1 Column 2, at end of NOTE, append: , at least once a day.
- page 3-5 Para 3.2.6, line 2. Change from "handers" to: handlers. Para 3.2.6, step c, line 5. Change from "the the" to: the.
- page 3-9 Para 3.4.3, step d. Add: (The displayed number may change very slightly, reflecting use of binary math in the CPU.)
- page 3-16 After para 3.8, insert: CAUTION Be sure Digibridge power is OFF while any connections are made or broken at the IEEE-488 INTERFACE connector or its cable. Otherwise, calibration may be lost.

*Refer to the back of this notice.

September 14, 1978

Form No. *1687-0121* ³⁰⁰ BAKER AVENUE, CONCORD MASSACHUSETTS ⁰¹⁷⁴² *Printed in U.S.A.*

page 5-4 page 5-5 page 5-6 Table 5-3, column 3, line 5. Change from "1406-9700" to 1405-9700. Line 6. Change from "1406-9703" to 1405-9703.
Line 20. Change from "2540" to 3500. Change from "2540" to 3500. After line 3, insert: Adaptor (2 required) $GR874^{\circled{6}}$ and binding posts GR 0874-9870 (-Q2) Para 5.5.3, step h. Change from " $-\emptyset$.020" to $-\emptyset$.085. Change from μ ,020 (max)" to \emptyset .085 (max). Para 5.5.6, step b, line 2. Change "GP" to Gp. Para 5.5.7, line 6. Add: ; use binding-post adaptors.

page $5-10$ Table $5-10$, column 5, lines 5 & 6. Change "B10" to B2.

New information that belongs just before para 2.8:

Refer to Figure 2-2A for timing guidelines. Notice that START must have a duration of 1 μ s (minimum) in each state (high and low). If STAAT is provided by a mechanical switch without debounce circuitry, the Oigibridge will make many false starts; but these will not cause extraneous testresult signals if STAAT is made to settle down (low) within 20 ms (maximum) of the first transition to high.

Measurement starts at time d, which is essentially the same as time b or c; measurement is completed at e. (The START signals are expanded for clarity.) Interval d-e, during which the OUT must remain connected, is 150 ms for FAST or 300 ms for SLOW MEASURE RATE. After interval e-f, which is 50 ms, measurement results are available for sorting, i.e., one of the BIN lines goes low. A few microseconds later, EOT goes low (can be used to set a latch holding the bin assignment). ACQ OVER, the selected BIN line, and EOT then stay low until the next start command.

Be sure the TALK switch is set to TALK ONLY, if the IEEE-488 bus is not used.

Figure 2-2A. Handler interface timing diagram. External circuitry must keep a-b > 1 μ s, b-a > 1 μ s, and (if START is not "debounced") $a-c < 20$ ms. The OUT can be disconnected after "e." The selected "BIN" line goes low at "f"; the others stay high.

New information that belongs just before para 2.9:

2.8.5 Programming Guidelines.

If the Digibridge is to be programmed (TALK switch set to TALK/LISTEN), keep the following suggestions in mind.

1. An "unlisten" command is required before measurement is possible.

2. If not addressed to talk, the Digibridge sends a service request (SRQ low) when it has data ready to send.

3. Then SAO will not go false (high) until the Digibridge has been addressed to talk or has been serially polled.

A typical program might include these features:

• Initial setup: with ATN true, "untalk, unlisten, my listen address (of Digibridge), my talk address (of CPU)"; then with ATN false, measurement conditions (Table 2-3).

• Measurement-enabling sequence, for example: untalk the Digibridge, send a GET, unlisten the Digibridge.

• After CPU receives the SRO, necessary enabling of data transfer: with ATN true, "untalk, unlisten, my listen address (of CPU), my talk address (of Digibridge)"; then ATN false.

Baker Ave, Concord, MA 01742

